Freescale Semiconductor
Data Sheet: Product Preview

Document Number: K30P81M100SF2
Rev. 4, 3/2011

K30P81M100SF2

K30 Sub-Family Data Sheet

Supports the following:
MK30N512VLK100, MK30N512VMB100

Features

- Operating Characteristics
  - Voltage range: 1.71 to 3.6 V
  - Flash write voltage range: 1.71 to 3.6 V
  - Temperature range (ambient): -40 to 105°C
- Performance
  - Up to 100 MHz ARM Cortex-M4 core with DSP instructions delivering 1.25 Dhrystone MIPS per MHz
- Memories and memory interfaces
  - Up to 512 KB program flash memory on non-FlexMemory devices
  - Up to 128 KB RAM
  - Serial programming interface (EzPort)
- Clocks
  - 3 to 32 MHz crystal oscillator
  - 32 kHz crystal oscillator
  - Multi-purpose clock generator
- System peripherals
  - 10 low-power modes to provide power optimization based on application requirements
  - Memory protection unit with multi-master protection
  - 16-channel DMA controller, supporting up to 64 request sources
  - External watchdog monitor
  - Software watchdog
  - Low-leakage wakeup unit
- Security and integrity modules
  - Hardware CRC module to support fast cyclic redundancy checks
  - 128-bit unique identification (ID) number per chip
- Human-machine interface
  - Segment LCD controller supporting up to 40 frontplanes and 8 backplanes, or 44 frontplanes and 4 backplanes
  - Low-power hardware touch sensor interface (TSI)
  - General-purpose input/output
- Analog modules
  - Two 16-bit SAR ADCs
  - Programmable gain amplifier (up to x64) integrated into each ADC
  - 12-bit DAC
  - Three analog comparators (CMP) containing a 6-bit DAC and programmable reference input
  - Voltage reference
- Timers
  - Programmable delay block
  - Eight-channel motor control/general purpose/PWM timer
  - Two 2-channel quadrature decoder/general purpose timers
  - Periodic interrupt timers
  - 16-bit low-power timer
  - Carrier modulator transmitter
  - Real-time clock
- Communication interfaces
  - Controller Area Network (CAN) module
  - Two SPI modules
  - Two I2C modules
  - Four UART modules
  - Secure Digital host controller (SDHC)
  - I2S module

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Preliminary

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1 Ordering parts

1.1 Determining valid orderable parts

Valid orderable part numbers are provided on the web. To determine the orderable part numbers for this device, go to http://www.freescale.com and perform a part number search for the following device numbers: PK30 and MK30.

2 Part identification

2.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

2.2 Format

Part numbers for this device have the following format:

Q K## M FFF T PP CCC N

2.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
Q	Qualification status	• M = Fully qualified, general market flow • P = Prequalification
K##	Kinetis family	• K30
M	Flash memory type	• N = Program flash only • X = Program flash and FlexMemory

Table continues on the next page...

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Field	Description	Values
FFF	Program flash memory size	• 32 = 32 KB • 64 = 64 KB • 128 = 128 KB • 256 = 256 KB • 512 = 512 KB • 1M0 = 1 MB
T	Temperature range (°C)	• V = –40 to 105 • C = –40 to 85
PP	Package identifier	• FM = 32 QFN (5 mm x 5 mm) • FT = 48 QFN (7 mm x 7 mm) • LF = 48 LQFP (7 mm x 7 mm) • EX = 64 QFN (9 mm x 9 mm) • LH = 64 LQFP (10 mm x 10 mm) • LK = 80 LQFP (12 mm x 12 mm) • MB = 81 MAPBGA (8 mm x 8 mm) • LL = 100 LQFP (14 mm x 14 mm) • MC = 121 MAPBGA (8 mm x 8 mm) • LQ = 144 LQFP (20 mm x 20 mm) • MD = 144 MAPBGA (13 mm x 13 mm) • MF = 196 MAPBGA (15 mm x 15 mm) • MJ = 256 MAPBGA (17 mm x 17 mm)
CCC	Maximum CPU frequency (MHz)	• 50 = 50 MHz • 72 = 72 MHz • 100 = 100 MHz • 120 = 120 MHz • 150 = 150 MHz
N	Packaging type	• R = Tape and reel • (Blank) = Trays

2.4 Example

This is an example part number:

MK30N512VMD100

3 Terminology and guidelines

3.1 Definition: Operating requirement

An *operating requirement* is a specified value or range of values for a technical characteristic that you must guarantee during operation to avoid incorrect operation and possibly decreasing the useful life of the chip.

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3.1.1 Example

This is an example of an operating requirement, which you must meet for the accompanying operating behaviors to be guaranteed:

Symbol	Description	Min.	Max.	Unit
V_{DD}	1.0 V core supply voltage	0.9	1.1	V

3.2 Definition: Operating behavior

An *operating behavior* is a specified value or range of values for a technical characteristic that are guaranteed during operation if you meet the operating requirements and any other specified conditions.

3.2.1 Example

This is an example of an operating behavior, which is guaranteed if you meet the accompanying operating requirements:

Symbol	Description	Min.	Max.	Unit
I_{WP}	Digital I/O weak pullup/ pulldown current	10	130	µA

3.3 Definition: Attribute

An *attribute* is a specified value or range of values for a technical characteristic that are guaranteed, regardless of whether you meet the operating requirements.

3.3.1 Example

This is an example of an attribute:

Symbol	Description	Min.	Max.	Unit
CIN_D	Input capacitance: digital pins	—	7	pF

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3.4 Definition: Rating

A *rating* is a minimum or maximum value of a technical characteristic that, if exceeded, may cause permanent chip failure:

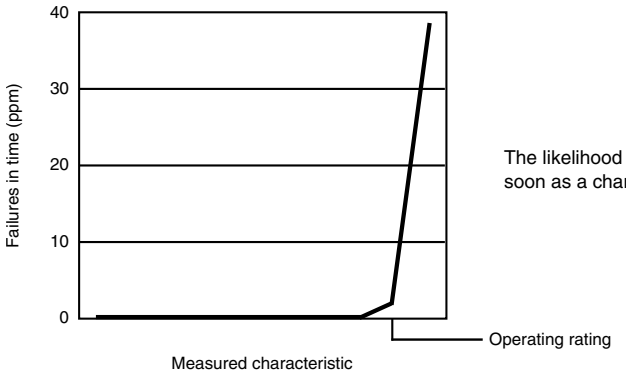
- *Operating ratings* apply during operation of the chip.
- *Handling ratings* apply when the chip is not powered.

3.4.1 Example

This is an example of an operating rating:

Symbol	Description	Min.	Max.	Unit
V_{DD}	1.0 V core supply voltage	–0.3	1.2	V

3.5 Result of exceeding a rating



The likelihood of permanent chip failure increases rapidly as soon as a characteristic begins to exceed one of its operating ratings.

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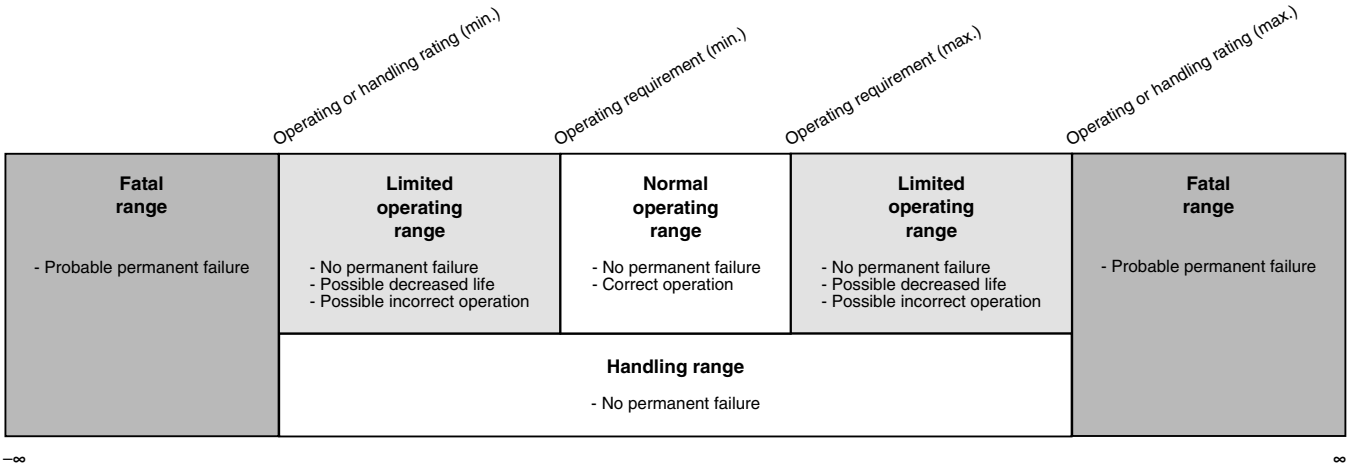
3.6 Relationship between ratings and operating requirements



3.7 Guidelines for ratings and operating requirements

Follow these guidelines for ratings and operating requirements:

- Never exceed any of the chip's ratings.
- During normal operation, don't exceed any of the chip's operating requirements.
- If you must exceed an operating requirement at times other than during normal operation (for example, during power sequencing), limit the duration as much as possible.

3.8 Definition: Typical value

A *typical value* is a specified value for a technical characteristic that:

- Lies within the range of values specified by the operating behavior
- Given the typical manufacturing process, is representative of that characteristic during operation when you meet the typical-value conditions or other specified conditions

Typical values are provided as design guidelines and are neither tested nor guaranteed.

3.8.1 Example 1

This is an example of an operating behavior that includes a typical value:

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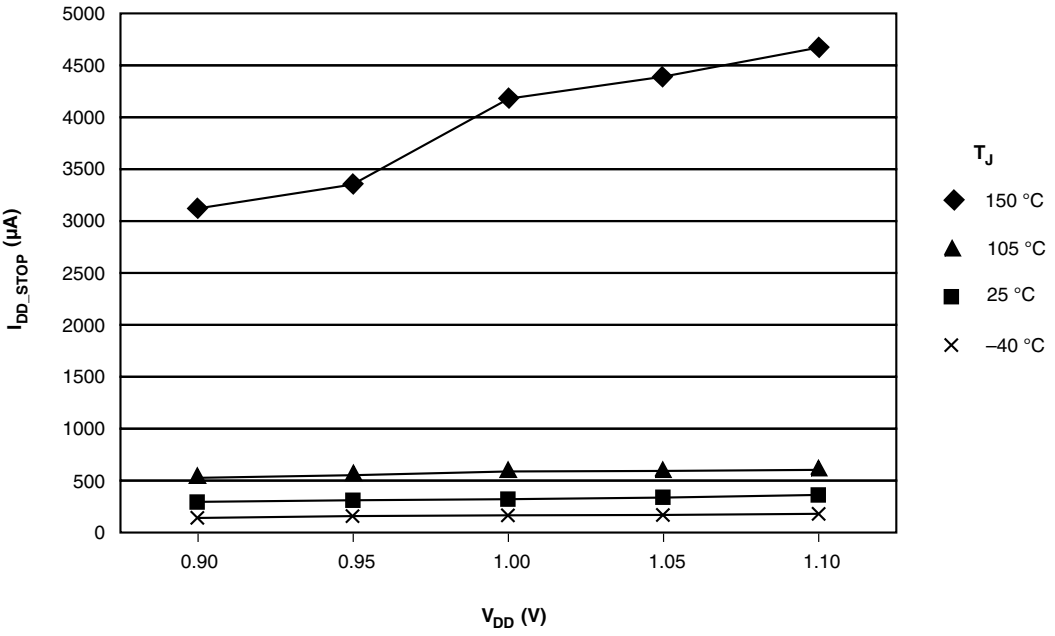
Symbol	Description	Min.	Typ.	Max.	Unit
I_{WP}	Digital I/O weak pullup/pulldown current	10	70	130	µA

3.8.2 Example 2

This is an example of a chart that shows typical values for various voltage and temperature conditions:



3.9 Typical value conditions

Typical values assume you meet the following conditions (or other conditions as specified):

Symbol	Description	Value	Unit
T_A	Ambient temperature	25	°C
V_{DD}	3.3 V supply voltage	3.3	V

4 Ratings

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4.1 Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T_{STG}	Storage temperature	–55	150	°C	1
T_{SDR}	Solder temperature, lead-free	—	260	°C	2
	Solder temperature, leaded	—	245		

1. Determined according to JEDEC Standard JESD22-A103, *High Temperature Storage Life*.
2. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.2 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	—	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.3 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V_{HBM}	Electrostatic discharge voltage, human body model	-2000	+2000	V	1
V_{CDM}	Electrostatic discharge voltage, charged-device model	-500	+500	V	2
I_{LAT}	Latch-up current at ambient temperature of 85°C	-100	+100	mA	

1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
2. Determined according to JEDEC Standard JESD22-C101, *Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components*.

4.4 Voltage and current operating ratings

Symbol	Description	Min.	Max.	Unit
V_{DD}	Digital supply voltage	–0.3	3.8	V
I_{DD}	Digital supply current	—	185	mA
V_{DIO}	Digital input voltage (except $\overline{\text{RESET}}$, EXTAL, and XTAL)	–0.3	5.5	V

Table continues on the next page...

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Symbol	Description	Min.	Max.	Unit
V_{AIO}	Analog, $\overline{\text{RESET}}$, EXTAL, and XTAL input voltage	–0.3	V_{DD} + 0.3	V
I_D	Instantaneous maximum current single pin limit (applies to all port pins)	–25	25	mA
V_{DDA}	Analog supply voltage	V_{DD} – 0.3	V_{DD} + 0.3	V
V_{BAT}	RTC battery supply voltage	–0.3	3.8	V

5 General

5.1 Nonswitching electrical specifications

5.1.1 Voltage and current operating requirements

Table 1. Voltage and current operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
V_{DD}	Supply voltage	1.71	3.6	V	
V_{DDA}	Analog supply voltage	1.71	3.6	V	
$V_{DD} – V_{DDA}$	V_{DD}-to-V_{DDA} differential voltage	–0.1	0.1	V	
$V_{SS} – V_{SSA}$	V_{SS}-to-V_{SSA} differential voltage	–0.1	0.1	V	
V_{BAT}	RTC battery supply voltage	1.71	3.6	V	
V_{IH}	Input high voltage • 2.7 V ≤ V_{DD} ≤ 3.6 V • 1.7 V ≤ V_{DD} ≤ 2.7 V	 0.7 × V_{DD} 0.75 × V_{DD}	 — —	 V V	
V_{IL}	Input low voltage • 2.7 V ≤ V_{DD} ≤ 3.6 V • 1.7 V ≤ V_{DD} ≤ 2.7 V	 — —	 0.35 × V_{DD} 0.3 × V_{DD}	 V V	
V_{HYS}	Input hysteresis	0.06 × V_{DD}	—	V	
I_{IC}	DC injection current — single pin • V_{IN} < V_{SS}	0	–0.2	mA	1
	DC injection current — total MCU limit, includes sum of all stressed pins • V_{IN} < V_{SS}	0	–5	mA	1
V_{RAM}	V_{DD} voltage required to retain RAM	1.2	—	V	
V_{RFVBAT}	V_{BAT} voltage required to retain the VBAT register file	TBD	—	V	

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1. All functional non-supply pins are internally clamped to V_{SS}, and induce an injection current when V_{IN} is less than V_{SS}. The I_{IC} maximum operating requirement should not be exceeded. If this requirement cannot be met, the input must be current limited to the value specified.

5.1.2 LVD and POR operating requirements

Table 2. V_{DD} supply LVD and POR operating requirements

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{POR}	Falling VDD POR detect voltage	TBD	1.1	TBD	V	
V_{LVDH}	Falling low-voltage detect threshold — high range (LVDV=01)	TBD	2.56	TBD	V	
	Low-voltage warning thresholds — high range					1
V_{LVW1H}	• Level 1 falling (LVWV=00)	TBD	2.70	TBD	V	
V_{LVW2H}	• Level 2 falling (LVWV=01)	TBD	2.80	TBD	V	
V_{LVW3H}	• Level 3 falling (LVWV=10)	TBD	2.90	TBD	V	
V_{LVW4H}	• Level 4 falling (LVWV=11)	TBD	3.00	TBD	V	
V_{HYSH}	Low-voltage inhibit reset/recover hysteresis — high range		60		mV	
V_{LVDL}	Falling low-voltage detect threshold — low range (LVDV=00)	TBD	1.60	TBD	V	
	Low-voltage warning thresholds — low range					1
V_{LVW1L}	• Level 1 falling (LVWV=00)	TBD	1.80	TBD	V	
V_{LVW2L}	• Level 2 falling (LVWV=01)	TBD	1.90	TBD	V	
V_{LVW3L}	• Level 3 falling (LVWV=10)	TBD	2.00	TBD	V	
V_{LVW4L}	• Level 4 falling (LVWV=11)	TBD	2.10	TBD	V	
V_{HYSL}	Low-voltage inhibit reset/recover hysteresis — low range		40		mV	
V_{BG}	Bandgap voltage reference	TBD	1.00	TBD	V	
t_{LPO}	Internal low power oscillator period factory trimmed	TBD	1000	TBD	µs	

1. Rising thresholds are falling threshold + hysteresis voltage

Table 3. VBAT power operating requirements

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{POR_VBAT}	Falling VBAT supply POR detect voltage	TBD	1.1	TBD	V	

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5.1.3 Voltage and current operating behaviors

Table 4. Voltage and current operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
V_{OH}	Output high voltage — high drive strength				
	• 2.7 V ≤ V_{DD} ≤ 3.6 V, I_{OH} = -10mA	V_{DD} – 0.5	—	V	
	• 1.71 V ≤ V_{DD} ≤ 2.7 V, I_{OH} = -3mA	V_{DD} – 0.5	—	V	
	Output high voltage — low drive strength				
	• 2.7 V ≤ V_{DD} ≤ 3.6 V, I_{OH} = -2mA	V_{DD} – 0.5	—	V	
	• 1.71 V ≤ V_{DD} ≤ 2.7 V, I_{OH} = -0.6mA	V_{DD} – 0.5	—	V	
I_{OHT}	Output high current total for all ports	—	100	mA	
V_{OL}	Output low voltage — high drive strength				
	• 2.7 V ≤ V_{DD} ≤ 3.6 V, I_{OL} = 10mA	—	0.5	V	
	• 1.71 V ≤ V_{DD} ≤ 2.7 V, I_{OL} = 3mA	—	0.5	V	
	Output low voltage — low drive strength				
	• 2.7 V ≤ V_{DD} ≤ 3.6 V, I_{OL} = 2mA	—	0.5	V	
	• 1.71 V ≤ V_{DD} ≤ 2.7 V, I_{OL} = 0.6mA	—	0.5	V	
I_{OLT}	Output low current total for all ports	—	100	mA	
I_{IN}	Input leakage current (per pin)	—	1	µA	1
I_{OZ}	Hi-Z (off-state) leakage current (per pin)	—	1	µA	
R_{PU}	Internal pullup resistors	30	50	kΩ	2
R_{PD}	Internal pulldown resistors	30	50	kΩ	3

1. Measured at VDD=3.6V
2. Measured at V_{DD} supply voltage = V_{DD} min and Vinput = V_{SS}
3. Measured at V_{DD} supply voltage = V_{DD} min and Vinput = V_{DD}

5.1.4 Power mode transition operating behaviors

All specifications except t_{POR}, and VLLSx→RUN recovery times in the following table assume this clock configuration:

- CPU and system clocks = 100 MHz
- Bus clock = 50 MHz
- Flash clock = 25 MHz

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Table 5. Power mode transition operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
t_{POR}	After a POR event, amount of time from the point V_{DD} reaches 1.8V to execution of the first instruction across the operating temperature range of the chip.	—	300	µs	1
	RUN → VLLS1 → RUN				
	• RUN → VLLS1	—	4.1	µs	
	• VLLS1 → RUN	—	123.8	µs	
	RUN → VLLS2 → RUN				
	• RUN → VLLS2	—	4.1	µs	
	• VLLS2 → RUN	—	49.3	µs	
	RUN → VLLS3 → RUN				
	• RUN → VLLS3	—	4.1	µs	
	• VLLS3 → RUN	—	49.2	µs	
	RUN → LLS → RUN				
	• RUN → LLS	—	4.1	µs	
	• LLS → RUN	—	5.9	µs	
	RUN → STOP → RUN				
	• RUN → STOP	—	4.1	µs	
	• STOP → RUN	—	4.2	µs	
	RUN → VLPS → RUN				
	• RUN → VLPS	—	4.1	µs	
	• VLPS → RUN	—	5.8	µs	

1. Normal boot (FTFL_OPT[LPBOOT]=1)

5.1.5 Power consumption operating behaviors

Table 6. Power consumption operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DDA}	Analog supply current	—	—	TBD	mA	1
I_{DD_RUN}	Run mode current — all peripheral clocks disabled, code executing from flash					2
	• @ 1.8V	—	40	TBD	mA	
	• @ 3.0V	—	42	TBD	mA	

Table continues on the next page...

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Table 6. Power consumption operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DD_RUN}	Run mode current — all peripheral clocks enabled, code executing from flash					3
	• @ 1.8V	—	55	TBD	mA	
	• @ 3.0V	—	56	TBD	mA	
$I_{DD\_RUN\_MAX}$	Run mode current — all peripheral clocks enabled and peripherals active, code executing from flash					4
	• @ 1.8V	—	85	TBD	mA	
	• @ 3.0V	—	85	TBD	mA	
I_{DD_WAIT}	Wait mode high frequency current at 3.0 V — all peripheral clocks disabled	—	35	TBD	mA	2
I_{DD_WAIT}	Wait mode reduced frequency current at 3.0 V — all peripheral clocks disabled	—	15	TBD	mA	5
I_{DD_STOP}	Stop mode current at 3.0 V	—	0.4	TBD	mA	
I_{DD_VLPR}	Very-low-power run mode current at 3.0 V — all peripheral clocks disabled	—	1.25	TBD	mA	6
I_{DD_VLPR}	Very-low-power run mode current at 3.0 V — all peripheral clocks enabled	—	TBD	TBD	mA	7
I_{DD_VLPW}	Very-low-power wait mode current at 3.0 V	—	1.05	TBD	mA	8
I_{DD_VLPS}	Very-low-power stop mode current at 3.0 V	—	50	TBD	µA	
I_{DD_LLS}	Low leakage stop mode current at 3.0 V	—	12	TBD	µA	
I_{DD_VLLS3}	Very low-leakage stop mode 3 current at 3.0 V					
	• 128KB RAM devices	—	8	TBD	µA	
I_{DD_VLLS2}	Very low-leakage stop mode 2 current at 3.0 V	—	4	TBD	µA	
I_{DD_VLLS1}	Very low-leakage stop mode 1 current at 3.0 V	—	2	TBD	µA	
I_{DD_VBAT}	Average current when CPU is not accessing RTC registers at 3.0 V	—	550	TBD	nA	9

1. The analog supply current is the sum of the active or disabled current for each of the analog modules on the device. See each module's specification for its supply current.
2. 100MHz core and system clock, 50MHz bus clock, and 25MHz flash clock . MCG configured for FEI mode. All peripheral clocks disabled.
3. 100MHz core and system clock, 50MHz bus clock, and 25MHz flash clock. MCG configured for FEI mode. All peripheral clocks enabled, but peripherals are not in active operation.
4. 100MHz core and system clock, 50MHz bus clock, and 25MHz flash clock. MCG configured for FEI mode. All peripheral clocks enabled, and peripherals are in active operation.
5. 25MHz core and system clock, 25MHz bus clock, and 12.5MHz flash clock. MCG configured for FEI mode.
6. 2 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for fast IRCLK mode. All peripheral clocks disabled. Code executing from flash.
7. 2 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for fast IRCLK mode. All peripheral clocks enabled but peripherals are not in active operation. Code executing from flash.
8. 2 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for fast IRCLK mode. All peripheral clocks disabled.
9. Includes 32kHz oscillator current and RTC operation.

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5.1.5.1 Diagram: Typical IDD_RUN operating behavior

The following data was measured under these conditions:

- MCG in FEI mode (39.0625 kHz IRC), except for 1 MHz core (FBE)
- All peripheral clocks disabled except FTFL
- LVD disabled
- No GPIOs toggled
- Code execution from flash

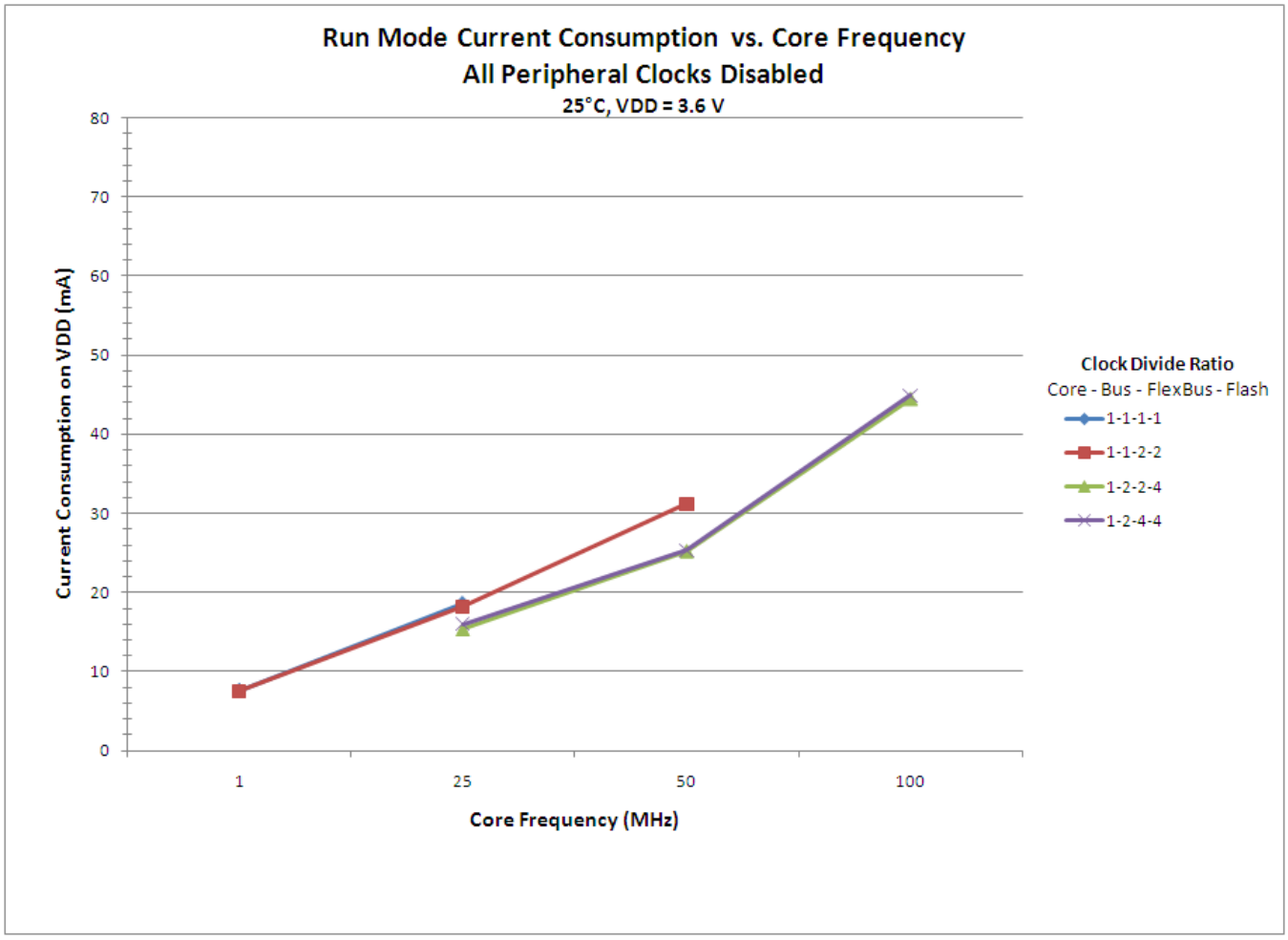

Figure 1. Run mode supply current vs. core frequency — all peripheral clocks disabled

The following data was measured under these conditions:

- MCG in FEI mode (39.0625 kHz IRC), except for 1 MHz core (FBE)
- All peripheral clocks enabled but peripherals are not in active operation
- LVD disabled
- No GPIOs toggled
- Code execution from flash

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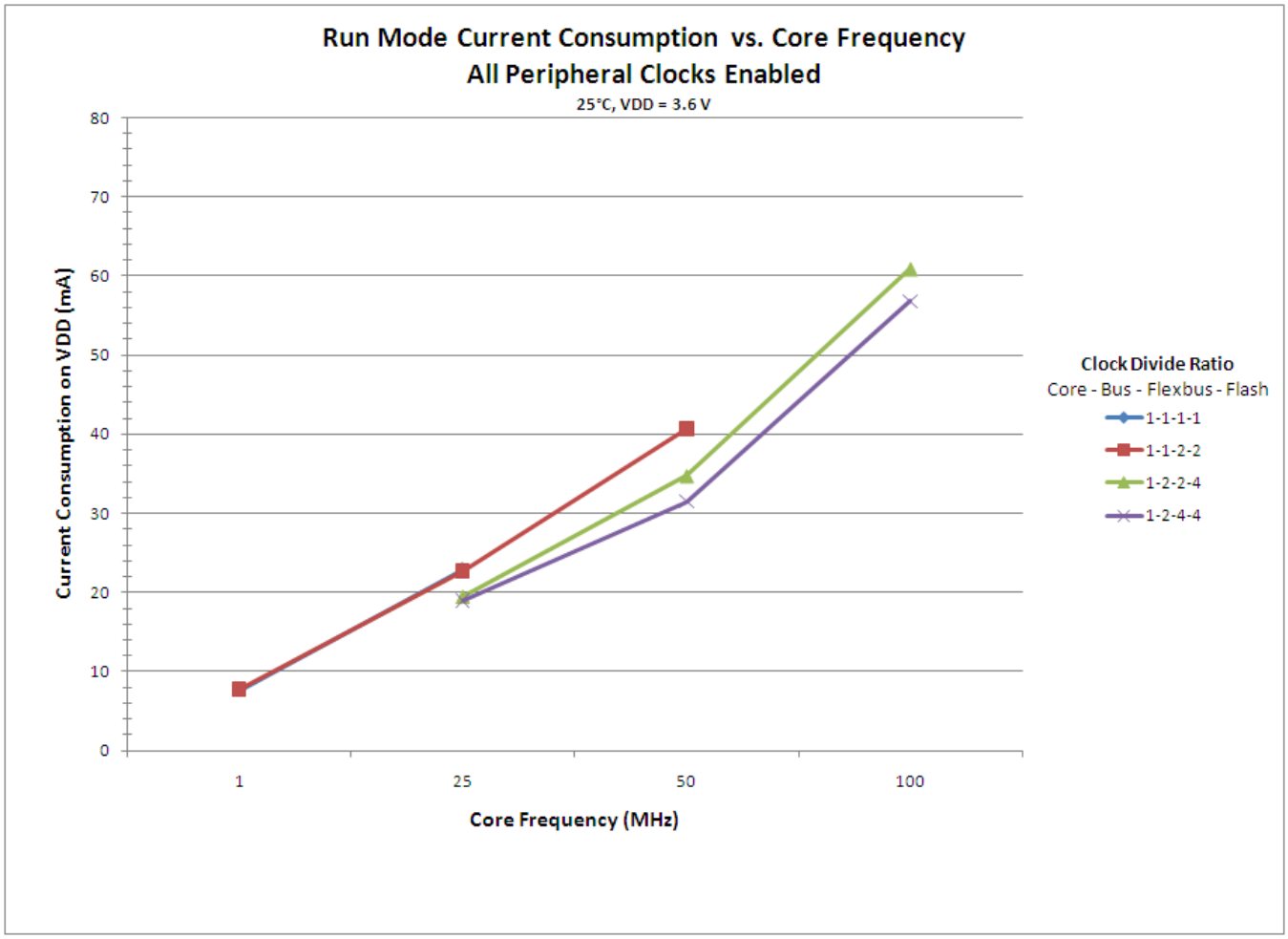

Figure 2. Run mode supply current vs. core frequency — all peripheral clocks enabled

5.1.6 EMC radiated emissions operating behaviors

Table 7. EMC radiated emissions operating behaviors

Symbol	Description	Frequency band (MHz)	Typ.	Unit	Notes
V_{RE1}	Radiated emissions voltage, band 1	0.15–50	TBD	dBµV	1, 2
V_{RE2}	Radiated emissions voltage, band 2	50–150	TBD		
V_{RE3}	Radiated emissions voltage, band 3	150–500	TBD		
V_{RE4}	Radiated emissions voltage, band 4	500–1000	TBD		
$V_{RE\_IEC\_SAE}$	IEC and SAE level	0.15–1000	TBD	—	2, 3

1. Determined according to IEC Standard 61967-1, *Integrated Circuits - Measurement of Electromagnetic Emissions, 150 kHz to 1 GHz Part 1: General Conditions and Definitions*, IEC Standard 61967-2, *Integrated Circuits - Measurement of Electromagnetic Emissions, 150 kHz to 1 GHz Part 2: Measurement of Radiated Emissions—TEM Cell and Wideband TEM Cell Method*, and SAE Standard J1752-3, *Measurement of Radiated Emissions from Integrated Circuits—TEM/ Wideband TEM (GTEM) Cell Method*.
2. V_{DD} = 3 V, T_A = 25 °C, f_{OSC} = 12 MHz (crystal), f_{SYS} = 96 MHz

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3. Specified according to Annex D of IEC Standard 61967-2, *Measurement of Radiated Emissions—TEM Cell and Wideband TEM Cell Method*, and Appendix D of SAE Standard J1752-3, *Measurement of Radiated Emissions from Integrated Circuits—TEM/Wideband TEM (GTEM) Cell Method*.

5.1.7 Designing with radiated emissions in mind

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions:

1. Go to http://www.freescale.com.
2. Perform a keyword search for "EMC design."

5.1.8 Capacitance attributes

Table 8. Capacitance attributes

Symbol	Description	Min.	Max.	Unit
C_{IN_A}	Input capacitance: analog pins	—	7	pF
C_{IN_D}	Input capacitance: digital pins	—	7	pF

5.2 Switching specifications

5.2.1 Device clock specifications

Symbol	Description	Min.	Max.	Unit	Notes
Normal run mode					
f_{SYS}	System and core clock	—	100	MHz	
f_{BUS}	Bus clock	—	50	MHz	
f_{FLASH}	Flash clock	—	25	MHz	
VLPR mode					
f_{SYS}	System and core clock	—	2	MHz	
f_{BUS}	Bus clock	—	2	MHz	
f_{FLASH}	Flash clock	—	1	MHz	

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5.2.2 General switching specifications

These general purpose specifications apply to all signals configured for GPIO, UART, CAN, CMT, and I^2C signals.

Symbol	Description	Min.	Max.	Unit	Notes
	GPIO pin interrupt pulse width (digital glitch filter disabled) — Synchronous path	1.5	—	Bus clock cycles	1
	GPIO pin interrupt pulse width (digital glitch filter disabled, analog filter enabled) — Asynchronous path	100	—	ns	2
	GPIO pin interrupt pulse width (digital glitch filter disabled, analog filter disabled) — Asynchronous path	16	—	ns	2
	External reset pulse width (digital glitch filter disabled)	TBD	—		
	Mode select ($\overline{\text{EZP\_CS}}$) hold time after reset deassertion	2	—	Bus clock cycles	
	Port rise and fall time (high drive strength) • Slew disabled • Slew enabled	 — —	 12 36	 ns ns	3
	Port rise and fall time (low drive strength) • Slew disabled • Slew enabled	 — —	 32 36	 ns ns	4

1. The greater synchronous and asynchronous timing must be met.
2. This is the shortest pulse that is guaranteed to be recognized.
3. 75pF load
4. 15pF load

5.3 Thermal specifications

5.3.1 Thermal operating requirements

Table 9. Thermal operating requirements

Symbol	Description	Min.	Max.	Unit
T_J	Die junction temperature	–40	125	°C
T_A	Ambient temperature	–40	105	°C

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5.3.2 Thermal attributes

Board type	Symbol	Description	81 MAPBGA	80 LQFP	Unit	Notes
Single-layer (1s)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	TBD	TBD	°C/W	1
Four-layer (2s2p)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	TBD	TBD	°C/W	1
Single-layer (1s)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./min. air speed)	TBD	TBD	°C/W	1
Four-layer (2s2p)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./min. air speed)	TBD	TBD	°C/W	1
—	$R_{\theta JB}$	Thermal resistance, junction to board	TBD	TBD	°C/W	2
—	$R_{\theta JC}$	Thermal resistance, junction to case	TBD	TBD	°C/W	3
—	Ψ_{JT}	Thermal characterization parameter, junction to package top outside center (natural convection)	TBD	TBD	°C/W	4

1. Determined according to JEDEC Standard JESD51-2, *Integrated Circuits Thermal Test Method Environmental Conditions—Natural Convection (Still Air)*, or EIA/JEDEC Standard JESD51-6, *Integrated Circuit Thermal Test Method Environmental Conditions—Forced Convection (Moving Air)*.

6 Peripheral operating requirements and behaviors

All digital I/O switching characteristics assume:

1. output pins
   - have C_L=30pF loads,
   - are configured for fast slew rate (PORTx_PCRn[SRE]=0), and
   - are configured for high drive strength (PORTx_PCRn[DSE]=1)
2. input pins
   - have their passive filter disabled (PORTx_PCRn[PFE]=0)

6.1 Core modules

6.1.1 Debug trace timing specifications

Table 10. Debug trace operating behaviors

Symbol	Description	Min.	Max.	Unit
T_{cyc}	Clock period	Frequency dependent		MHz
T_{wl}	Low pulse width	2	—	ns

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Table 10. Debug trace operating behaviors (continued)

Symbol	Description	Min.	Max.	Unit
T_{wh}	High pulse width	2	—	ns
T_r	Clock and data rise time	—	3	ns
T_f	Clock and data fall time	—	3	ns
T_s	Data setup	3	—	ns
T_h	Data hold	2	—	ns

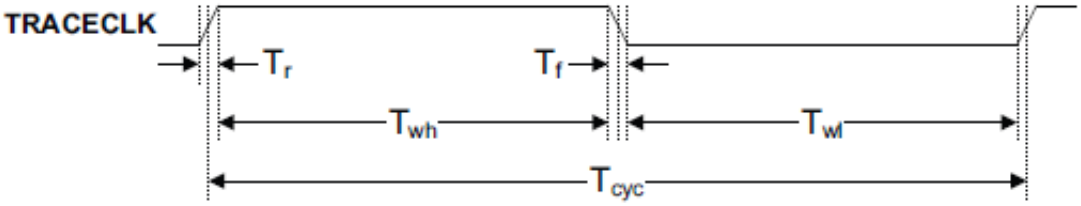

Figure 3. TRACE_CLKOUT specifications

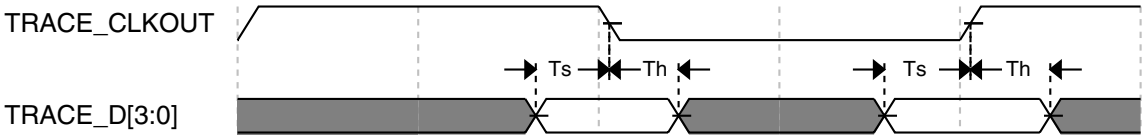

Figure 4. Trace data specifications

6.1.2 JTAG electricals

Table 11. JTAG limited voltage range electricals

Symbol	Description	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
J1	TCLK frequency of operation			MHz
	• Boundary Scan	0	10	
	• JTAG and CJTAG	0	25	
	• Serial Wire Debug	0	50	
J2	TCLK cycle period	1/J1	—	ns

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Table 11. JTAG limited voltage range electricals (continued)

Symbol	Description	Min.	Max.	Unit
J3	TCLK clock pulse width			ns
	• Boundary Scan	50	—	
	• JTAG and CJTAG	20	—	
	• Serial Wire Debug	10		
J4	TCLK rise and fall times	—	3	ns
J5	Boundary scan input data setup time to TCLK rise	20	—	ns
J6	Boundary scan input data hold time after TCLK rise	0	—	ns
J7	TCLK low to boundary scan output data valid	—	25	ns
J8	TCLK low to boundary scan output high-Z	—	25	ns
J9	TMS, TDI input data setup time to TCLK rise	8	—	ns
J10	TMS, TDI input data hold time after TCLK rise	1	—	ns
J11	TCLK low to TDO data valid	—	17	ns
J12	TCLK low to TDO high-Z	—	17	ns
J13	$\overline{\text{TRST}}$ assert time	100	—	ns
J14	$\overline{\text{TRST}}$ setup time (negation) to TCLK high	8	—	ns

Table 12. JTAG full voltage range electricals

Symbol	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
J1	TCLK frequency of operation			MHz
	• Boundary Scan	0	10	
	• JTAG and CJTAG	0	20	
	• Serial Wire Debug	0	40	
J2	TCLK cycle period	1/J1	—	ns
J3	TCLK clock pulse width			ns
	• Boundary Scan	50	—	
	• JTAG and CJTAG	25	—	
	• Serial Wire Debug	12.5		
J4	TCLK rise and fall times	—	3	ns
J5	Boundary scan input data setup time to TCLK rise	20	—	ns
J6	Boundary scan input data hold time after TCLK rise	0	—	ns
J7	TCLK low to boundary scan output data valid	—	25	ns
J8	TCLK low to boundary scan output high-Z	—	25	ns
J9	TMS, TDI input data setup time to TCLK rise	8	—	ns

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Table 12. JTAG full voltage range electricals (continued)

Symbol	Description	Min.	Max.	Unit
J10	TMS, TDI input data hold time after TCLK rise	1.4	—	ns
J11	TCLK low to TDO data valid	—	22.1	ns
J12	TCLK low to TDO high-Z	—	22.1	ns
J13	$\overline{\text{TRST}}$ assert time	100	—	ns
J14	$\overline{\text{TRST}}$ setup time (negation) to TCLK high	8	—	ns

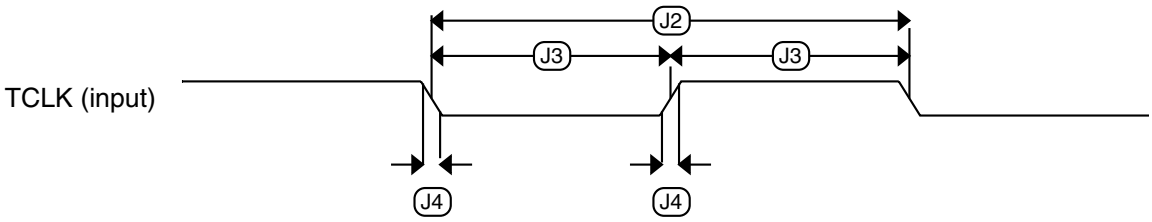

Figure 5. Test clock input timing

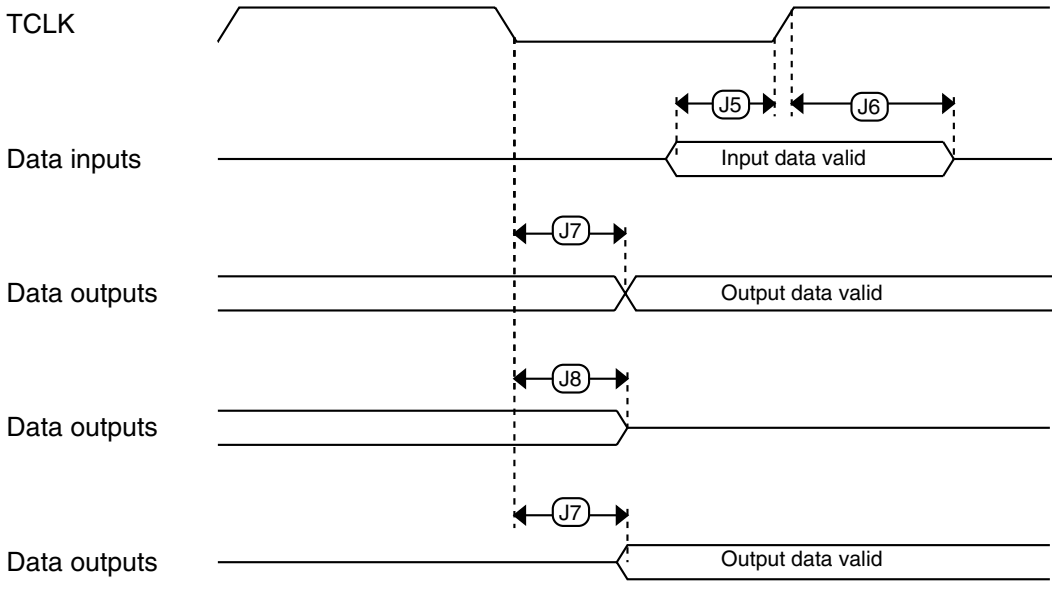

Figure 6. Boundary scan (JTAG) timing

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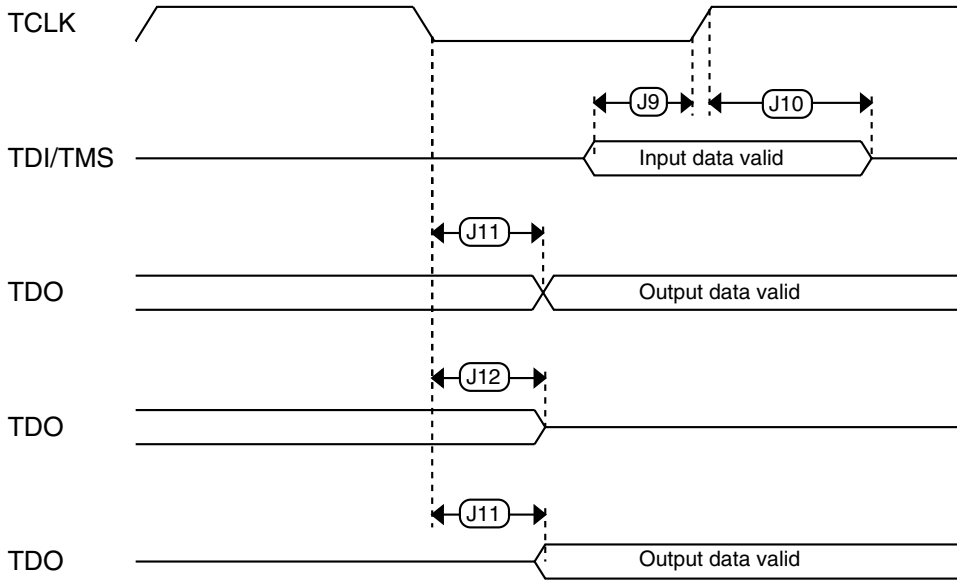

Figure 7. Test Access Port timing

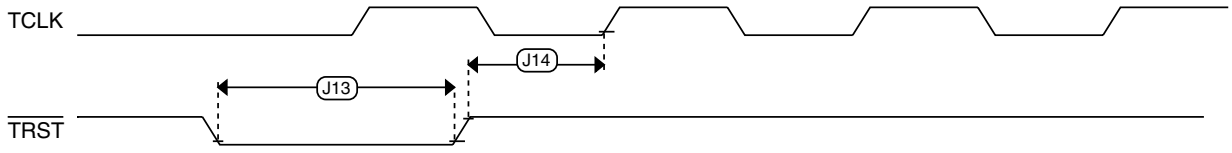

Figure 8. $\overline{\text{TRST}}$ timing

6.2 System modules

There are no specifications necessary for the device's system modules.

6.3 Clock modules

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6.3.1 MCG specifications

Table 13. MCG specifications

Symbol	Description		Min.	Typ.	Max.	Unit	Notes
f_{ints_ft}	Internal reference frequency (slow clock) — factory trimmed at nominal VDD and 25°C		—	32.768	—	kHz	
f_{ints_t}	Internal reference frequency (slow clock) — user trimmed		31.25	—	39.0625	kHz	
I_{ints}	Internal reference (slow clock) current		—	TBD	—	µA	
$t_{irefsts}$	Internal reference (slow clock) startup time		—	TBD	4	µs	
$\Delta_{fdco\_res\_t}$	Resolution of trimmed DCO output frequency at fixed voltage and temperature — using SCTRIM and SCFTRIM		—	± 0.1	± 0.3	$\%f_{dco}$	1
$\Delta f_{dco\_res\_t}$	Resolution of trimmed DCO output frequency at fixed voltage and temperature — using SCTRIM only		—	± 0.2	± 0.5	$\%f_{dco}$	1
Δf_{dco_t}	Total deviation of trimmed average DCO output frequency over voltage and temperature		—	+ 0.5 - 1.0	± 3.5	$\%f_{dco}$	1
Δf_{dco_t}	Total deviation of trimmed average DCO output frequency over fixed voltage and temperature range of 0–70°C		—	± 0.5	± TBD	$\%f_{dco}$	1
f_{intf_ft}	Internal reference frequency (fast clock) — factory trimmed at nominal VDD and 25°C		3.4	—	4	MHz	
f_{intf_t}	Internal reference frequency (fast clock) — user trimmed		3	—	5	MHz	
I_{intf}	Internal reference (fast clock) current		—	TBD	—	µA	
$t_{irefstf}$	Internal reference startup time (fast clock)		—	TBD	TBD	µs	
f_{loc_low}	Loss of external clock minimum frequency — RANGE = 00		(3/5) x f_{ints_t}	—	—	kHz	
f_{loc_high}	Loss of external clock minimum frequency — RANGE = 01, 10, or 11		(16/5) x f_{ints_t}	—	—	kHz	
FLL							
f_{fll_ref}	FLL reference frequency range		31.25	—	39.0625	kHz	
f_{dco}	DCO output frequency range	Low range (DRS=00) 640 × f_{fll_ref}	20	20.97	25	MHz	2, 3
		Mid range (DRS=01) 1280 × f_{fll_ref}	40	41.94	50	MHz	
		Mid-high range (DRS=10) 1920 × f_{fll_ref}	60	62.91	75	MHz	
		High range (DRS=11) 2560 × f_{fll_ref}	80	83.89	100	MHz	

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Table 13. MCG specifications (continued)

Symbol	Description		Min.	Typ.	Max.	Unit	Notes
$f_{dco\_t\_DMX32}$	DCO output frequency	Low range (DRS=00) $732 \times f_{fll\_ref}$	—	23.99	—	MHz	4, 5
		Mid range (DRS=01) $1464 \times f_{fll\_ref}$	—	47.97	—	MHz	
		Mid-high range (DRS=10) $2197 \times f_{fll\_ref}$	—	71.99	—	MHz	
		High range (DRS=11) $2929 \times f_{fll\_ref}$	—	95.98	—	MHz	
J_{cyc_fll}	FLL period jitter		—	TBD	TBD	ps	6
J_{acc_fll}	FLL accumulated jitter of DCO output over a 1µs time window		—	TBD	TBD	ps	6
$t_{fll\_acquire}$	FLL target frequency acquisition time		—	—	1	ms	7
PLL							
f_{vco}	VCO operating frequency		48.0	—	100	MHz	
I_{pll}	PLL operating current • PLL @ 96 MHz ($f_{osc\_hi\_1}$=8MHz, f_{pll_ref}=2MHz, VDIV multiplier=48)		—	950	—	µA	8
f_{pll_ref}	PLL reference frequency range		2.0	—	4.0	MHz	
J_{cyc_pll}	PLL period jitter		—	400	—	ps	9, 10
J_{acc_pll}	PLL accumulated jitter over 1µs window		—	TBD	—	ps	9, 10
D_{lock}	Lock entry frequency tolerance		± 1.49	—	± 2.98	%	
D_{unl}	Lock exit frequency tolerance		± 4.47	—	± 5.97	%	
t_{pll_lock}	Lock detector detection time		—	—	0.15 + 1075(1/f_{pll_ref})	ms	11

1. This parameter is measured with the internal reference (slow clock) being used as a reference to the FLL (FEI clock mode).
2. These typical values listed are with the slow internal reference clock (FEI) using factory trim and DMX32=0.
3. The resulting system clock frequencies should not exceed their maximum specified values. The DCO frequency deviation (Δf_{dco_t}) over voltage and temperature should be considered.
4. These typical values listed are with the slow internal reference clock (FEI) using factory trim and DMX32=1.
5. The resulting clock frequency must not exceed the maximum specified clock frequency of the device.
6. This specification was obtained at TBD frequency.
7. This specification applies to any time the FLL reference source or reference divider is changed, trim value is changed, DMX32 bit is changed, DRS bits are changed, or changing from FLL disabled (BLPE, BLPI) to FLL enabled (FEI, FEE, FBE, FBI). If a crystal/resonator is being used as the reference, this specification assumes it is already running.
8. Excludes any oscillator currents that are also consuming power while PLL is in operation.
9. This specification was obtained using a Freescale developed PCB. PLL jitter is dependent on the noise characteristics of each PCB and results will vary.
10. This specification was obtained at internal frequency of TBD.
11. This specification applies to any time the PLL VCO divider or reference divider is changed, or changing from PLL disabled (BLPE, BLPI) to PLL enabled (PBE, PEE). If a crystal/resonator is being used as the reference, this specification assumes it is already running.

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6.3.2 Oscillator electrical specifications

This section provides the electrical characteristics of the module.

6.3.2.1 Oscillator DC electrical specifications

Table 14. Oscillator DC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{DD}	Supply voltage	1.71	—	3.6	V	
I_{DDOSC}	Supply current — low-power mode (HGO=0)					1
	• 32 kHz	—	500	—	nA	
	• 4 MHz	—	200	—	µA	
	• 8 MHz	—	300	—	µA	
	• 16 MHz	—	700	—	µA	
	• 24 MHz	—	1.2	—	mA	
	• 32 MHz	—	1.5	—	mA	
I_{DDOSC}	Supply current — high gain mode (HGO=1)					1
	• 32 kHz	—	25	—	µA	
	• 4 MHz	—	400	—	µA	
	• 8 MHz	—	800	—	µA	
	• 16 MHz	—	1.5	—	mA	
	• 24 MHz	—	3	—	mA	
	• 32 MHz	—	4	—	mA	
C_x	EXTAL load capacitance	—	—	—		2, 3
C_y	XTAL load capacitance	—	—	—		2, 3
R_F	Feedback resistor — low-frequency, low-power mode (HGO=0)	—	—	—	MΩ	2, 4
	Feedback resistor — low-frequency, high-gain mode (HGO=1)	—	10	—	MΩ	
	Feedback resistor — high-frequency, low-power mode (HGO=0)	—	—	—	MΩ	
	Feedback resistor — high-frequency, high-gain mode (HGO=1)	—	1	—	MΩ	

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Table 14. Oscillator DC electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
R_S	Series resistor — low-frequency, low-power mode (HGO=0)	—	—	—	kΩ	
	Series resistor — low-frequency, high-gain mode (HGO=1)	—	200	—	kΩ	
	Series resistor — high-frequency, low-power mode (HGO=0)	—	—	—	kΩ	
	Series resistor — high-frequency, high-gain mode (HGO=1)	—	0	—	kΩ	
V_{pp}[5]	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, low-power mode (HGO=0)	—	0.6	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, high-gain mode (HGO=1)	—	V_{DD}	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, low-power mode (HGO=0)	—	0.6	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, high-gain mode (HGO=1)	—	V_{DD}	—	V	

1. V_{DD}=3.3 V, Temperature =25 °C
2. See crystal or resonator manufacturer's recommendation
3. C_x,C_y can be provided by using either the integrated capacitors or by using external components.
4. When low power mode is selected, R_F is integrated and must not be attached externally.
5. The EXTAL and XTAL pins should only be connected to required oscillator components and must not be connected to any other devices.

6.3.2.2 Oscillator frequency specifications

Table 15. Oscillator frequency specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f_{osc_lo}	Oscillator crystal or resonator frequency — low frequency mode (MCG_C2[RANGE]=00)	32	—	40	kHz	
$f_{osc\_hi\_1}$	Oscillator crystal or resonator frequency — high frequency mode (low range) (MCG_C2[RANGE]=01)	3	—	8	MHz	
$f_{osc\_hi\_2}$	Oscillator crystal or resonator frequency — high frequency mode (high range) (MCG_C2[RANGE]=1x)	8	—	32	MHz	
f_{ec_extal}	Input clock frequency (external clock mode)	—	—	50	MHz	1
t_{dc_extal}	Input clock duty cycle (external clock mode)	40	50	60	%	

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Table 15. Oscillator frequency specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
t_{cst}	Crystal startup time — 32 kHz low-frequency, low-power mode (HGO=0)	—	TBD	—	ms	2, 3
	Crystal startup time — 32 kHz low-frequency, high-gain mode (HGO=1)	—	800	—	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), low-power mode (HGO=0)	—	4	—	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), high-gain mode (HGO=1)	—	3	—	ms	

1. Other frequency limits may apply when external clock is being used as a reference for the FLL or PLL
2. Proper PC board layout procedures must be followed to achieve specifications.
3. Crystal startup time is defined as the time between the oscillator being enabled and the OSCINIT bit in the MCG_S register being set.

6.3.3 32kHz Oscillator Electrical Characteristics

This section describes the module electrical characteristics.

6.3.3.1 32kHz oscillator DC electrical specifications

Table 16. 32kHz oscillator DC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
V_{BAT}	Supply voltage	1.71	—	3.6	V
R_F	Internal feedback resistor	—	100	—	MΩ
C_{para}	Parasitical capacitance of EXTAL32 and XTAL32	—	2.5	—	pF
C_{load}	Internal load capacitance (programmable)	—	15	—	pF
V_{pp}	Peak-to-peak amplitude of oscillation	—	0.6	—	V

6.3.3.2 32kHz oscillator frequency specifications

Table 17. 32kHz oscillator frequency specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f_{osc_lo}	Oscillator crystal	—	32	—	kHz	
t_{start}	Crystal start-up time	—	1000	—	ms	1

1. Proper PC board layout procedures must be followed to achieve specifications.

6.4 Memories and memory interfaces

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6.4.1 Flash (FTFL) electrical specifications

This section describes the electrical characteristics of the FTFL module.

6.4.1.1 Flash timing specifications — program and erase

The following specifications represent the amount of time the internal charge pumps are active and do not include command overhead.

Table 18. NVM program/erase timing specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
t_{hvpgm4}	Longword Program high-voltage time	—	20	TBD	µs	
$t_{hversscr}$	Sector Erase high-voltage time	—	20	100	ms	1
$t_{hversblk256k}$	Erase Block high-voltage time for 256 KB	—	160	800	ms	1

1. Maximum time based on expectations at cycling end-of-life.

6.4.1.2 Flash timing specifications — commands

Table 19. Flash command timing specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
$t_{rd1blk256k}$	Read 1s Block execution time • 256 KB data flash	—	—	1.4	ms	
$t_{rd1sec2k}$	Read 1s Section execution time (flash sector)	—	—	40	µs	1
t_{pgmchk}	Program Check execution time	—	—	35	µs	1
t_{rdrsrc}	Read Resource execution time	—	—	35	µs	1
t_{pgm4}	Program Longword execution time	—	50	TBD	µs	
$t_{ersblk256k}$	Erase Flash Block execution time • 256 KB data flash	—	160	800	ms	2
t_{ersscr}	Erase Flash Sector execution time	—	20	100	ms	2
$t_{pgmsec512}$ $t_{pgmsec1k}$ $t_{pgmsec2k}$	Program Section execution time • 512 B flash • 1 KB flash • 2 KB flash	— — —	TBD TBD TBD	TBD TBD TBD	ms ms ms	
t_{rd1all}	Read 1s All Blocks execution time	—	—	2.8	ms	
t_{rdonce}	Read Once execution time	—	—	35	µs	1
$t_{pgmonce}$	Program Once execution time	—	50	TBD	µs	

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Table 19. Flash command timing specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
t_{ersall}	Erase All Blocks execution time	—	320	1600	ms	2
t_{vfykey}	Verify Backdoor Access Key execution time	—	—	35	µs	1

1. Assumes 25MHz flash clock frequency.
2. Maximum times for erase parameters based on expectations at cycling end-of-life.

6.4.1.3 Flash (FTFL) current and power specfications

Table 20. Flash (FTFL) current and power specfications

Symbol	Description	Typ.	Unit
I_{DD_PGM}	Worst case programming current in program flash	10	mA

6.4.1.4 Reliability specifications

Table 21. NVM reliability specifications

Symbol	Description	Min.	Typ.[1]	Max.	Unit	Notes
Program Flash						
$t_{nvmretp10k}$	Data retention after up to 10 K cycles	5	TBD	—	years	2
$t_{nvmretp1k}$	Data retention after up to 1 K cycles	10	TBD	—	years	2
$t_{nvmretp100}$	Data retention after up to 100 cycles	15	TBD	—	years	2
$n_{nvmcycp}$	Cycling endurance	10 K	TBD	—	cycles	3

1. Typical data retention values are based on intrinsic capability of the technology measured at high temperature derated to 25°C. For additional information on how Freescale defines typical data retention, please refer to Engineering Bulletin EB618.
2. Data retention is based on T_{javg} = 55°C (temperature profile over the lifetime of the application).
3. Cycling endurance represents number of program/erase cycles at -40°C ≤ T_j ≤ 125°C.

6.4.2 EzPort Switching Specifications

Table 22. EzPort switching specifications

Num	Description	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
EP1	EZP_CK frequency of operation (all commands except READ)	—	$f_{SYS}/2$	MHz
EP1a	EZP_CK frequency of operation (READ command)	—	$f_{SYS}/8$	MHz
EP2	$\overline{\text{EZP\_CS}}$ negation to next $\overline{\text{EZP\_CS}}$ assertion	2 x t_{EZP_CK}	—	ns
EP3	$\overline{\text{EZP\_CS}}$ input valid to EZP_CK high (setup)	5	—	ns
EP4	EZP_CK high to $\overline{\text{EZP\_CS}}$ input invalid (hold)	5	—	ns

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Table 22. EzPort switching specifications (continued)

Num	Description	Min.	Max.	Unit
EP5	EZP_D input valid to EZP_CK high (setup)	2	—	ns
EP6	EZP_CK high to EZP_D input invalid (hold)	5	—	ns
EP7	EZP_CK low to EZP_Q output valid (setup)	—	12	ns
EP8	EZP_CK low to EZP_Q output invalid (hold)	0	—	ns
EP9	$\overline{\text{EZP\_CS}}$ negation to EZP_Q tri-state	—	12	ns

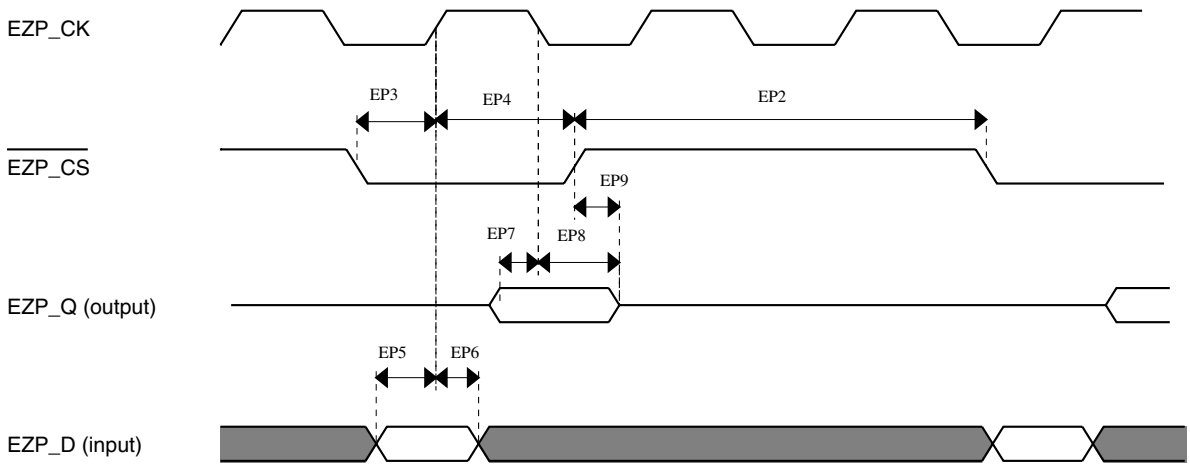

Figure 9. EzPort Timing Diagram

6.5 Security and integrity modules

There are no specifications necessary for the device's security and integrity modules.

6.6 Analog

6.6.1 ADC electrical specifications

The 16-bit accuracy specifications listed in Table 23 and Table 24 are achievable on the differential pins ADCx_DP0, ADCx_DM0, ADCx_DP1, ADCx_DM1, ADCx_DP3, and ADCx_DP3.

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The ADCx_DP2 and ADCx_DM2 ADC inputs are used as the PGA inputs and are not direct device pins. Accuracy specifications for these pins are defined in Table 25 and Table 26.

All other ADC channels meet the 13-bit differential/12-bit single-ended accuracy specifications.

6.6.1.1 16-bit ADC operating conditions

Table 23. 16-bit ADC operating conditions

Symbol	Description	Conditions	Min.	Typ.[1]	Max.	Unit	Notes
V_{DDA}	Supply voltage	Absolute	1.71	—	3.6	V	
ΔV_{DDA}	Supply voltage	Delta to V_{DD} (V_{DD}-V_{DDA})	-100	0	+100	mV	2
ΔV_{SSA}	Ground voltage	Delta to V_{SS} (V_{SS}-V_{SSA})	-100	0	+100	mV	2
V_{REFH}	ADC reference voltage high		1.13	V_{DDA}	V_{DDA}	V	
V_{REFL}	Reference voltage low		V_{SSA}	V_{SSA}	V_{SSA}	V	
V_{ADIN}	Input voltage		V_{REFL}	—	V_{REFH}	V	
C_{ADIN}	Input capacitance	• 16 bit modes • 8/10/12 bit modes	— —	8 4	10 5	pF	
R_{ADIN}	Input resistance		—	2	5	kΩ	
R_{AS}	Analog source resistance	13/12 bit modes f_{ADCK} < 4MHz	—	—	5	kΩ	3
f_{ADCK}	ADC conversion clock frequency	≤13 bit modes	1.0	—	18.0	MHz	4
f_{ADCK}	ADC conversion clock frequency	16 bit modes	2.0	—	12.0	MHz	5
C_{rate}	ADC conversion rate	≤13 bit modes No ADC hardware averaging Continuous conversions enabled Peripheral clock = 50MHz	18.484	—	818.330	Ksps	6

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Table 23. 16-bit ADC operating conditions (continued)

Symbol	Description	Conditions	Min.	Typ.[1]	Max.	Unit	Notes
C_{rate}	ADC conversion rate	16 bit modes No ADC hardware averaging Continuous conversions enabled Peripheral clock = 50MHz	37.037	—	361.402	Ksps	7

1. Typical values assume V_{DDA} = 3.0 V, Temp = 25°C, f_{ADCK} = 1.0 MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
2. DC potential difference.
3. This resistance is external to MCU. The analog source resistance should be kept as low as possible in order to achieve the best results. The results in this datasheet were derived from a system which has <8 Ω analog source resistance. The R_{AS}/C_{AS} time constant should be kept to <1ns.
4. In order to use the maximum ADC conversion clock frequency ADHSC bit should be set and the ADLPC should be clear.
5. In order to use the maximum ADC conversion clock frequency ADHSC bit should be set and the ADLPC should be clear.
6. For guidelines and examples of conversion rate calculation please download the ADC calculator tool http://cache.freescale.com/files/soft_dev_tools/software/app_software/converters/ADC_CALCULATOR_CNV.zip?fpsp=1
7. For guidelines and examples of conversion rate calculation please download the ADC calculator tool http://cache.freescale.com/files/soft_dev_tools/software/app_software/converters/ADC_CALCULATOR_CNV.zip?fpsp=1

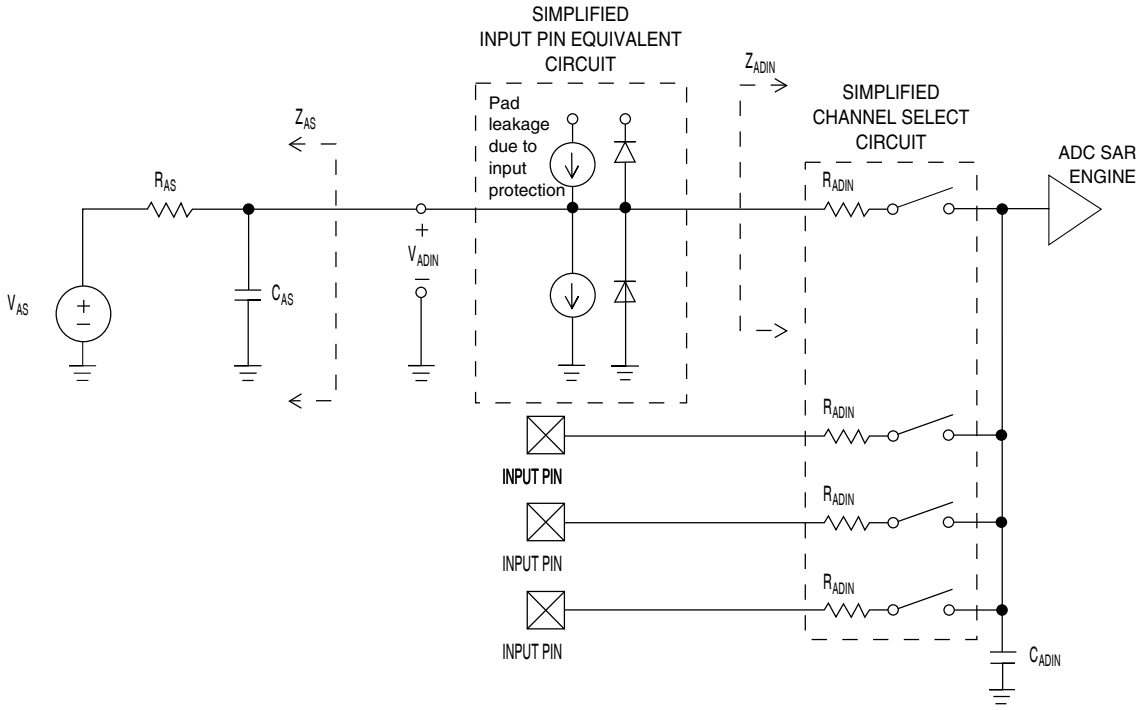

Figure 10. ADC input impedance equivalency diagram

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6.6.1.2 16-bit ADC electrical characteristics

Table 24. 16-bit ADC characteristics (V_{REFH} = V_{DDA}, V_{REFL} = V_{SSA})

Symbol	Description	Conditions[1]	Min.	Typ.[2]	Max.	Unit	Notes
I_{DDA}	Supply current		0.215	—	1.7	mA	3
f_{ADACK}	ADC asynchronous clock source	• ADLPC=1, ADHSC=0 • ADLPC=1, ADHSC=1 • ADLPC=0, ADHSC=0 • ADLPC=0, ADHSC=1	— — — —	2.4 4.0 5.2 6.2	— — — —	MHz MHz MHz MHz	t_{ADACK} = 1/ f_{ADACK}
	Sample Time	See Reference Manual chapter for sample times					
	Conversion Time	The ADC calculator tool can be used to determine ADC conversion times for different ADC configurations: http://cache.freescale.com/files/soft_dev_tools/software/app_software/converters/ADC_CALCULATOR_CNV.zip?fpsp=1					
TUE	Total unadjusted error	• ≤13 bit modes • <12 bit modes		±0.8 ±0.5	±TBD ±1	LSB[4]	ADC conversion clock <12MHz, Max hardware averaging (AVGE = %1, AVGS = %11)
DNL	Differential non-linearity	• ≤13 bit modes • <12 bit modes		±0.7 ±0.2	±TBD ±0.5	LSB[4]	ADC conversion clock <12MHz, Max hardware averaging (AVGE = %1, AVGS = %11)
INL	Integral non-linearity	• ≤13 bit modes • <12 bit modes	— —	±1.0 ±0.5	±TBD ±TBD	LSB[4]	Max averaging
E_{FS}	Full-scale error	• ≤13 bit modes • <12 bit modes	— —	±0.4 ±1.0	±TBD ±TBD	LSB[4]	V_{ADIN} = V_{DDA}
E_Q	Quantization error	• 16 bit modes • ≤13 bit modes	— —	-1 to 0 —	— ±0.5	LSB[4]	

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Table 24. 16-bit ADC characteristics (V_{REFH} = V_{DDA}, V_{REFL} = V_{SSA}) (continued)

Symbol	Description	Conditions[1]	Min.	Typ.[2]	Max.	Unit	Notes
ENOB	Effective number of bits	16 bit differential mode • Avg=32 • Avg=1 16 bit single-ended mode • Avg=32 • Avg=1	 TBD TBD TBD TBD	 13.6 13.2 TBD TBD	 TBD TBD TBD TBD	 bits bits bits bits	5
SINAD	Signal-to-noise plus distortion	See ENOB	6.02 × ENOB + 1.76			dB	
THD	Total harmonic distortion	16 bit differential mode • Avg=32 16 bit single-ended mode • Avg=32	 — —	 -94 TBD	 TBD TBD	 dB dB	5
SFDR	Spurious free dynamic range	16 bit differential mode • Avg=32 16 bit single-ended mode • Avg=32	 TBD TBD	 95 TBD	 — —	 dB dB	5
E_{IL}	Input leakage error		I_{In} × R_{AS}			mV	I_{In} = leakage current (refer to the MCU's voltage and current operating ratings)
	Temp sensor slope	• –40°C to 25°C • 25°C to 105°C	— —	TBD TBD	— —	mV/°C mV/°C	
V_{TEMP25}	Temp sensor voltage	25°C	—	TBD	—	mV	

1. All accuracy numbers assume the ADC is calibrated with V_{REFH} = V_{DDA}
2. Typical values assume V_{DDA} = 3.0 V, Temp = 25°C, f_{ADCK} = 2.0 MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
3. The ADC supply current depends on the ADC conversion clock speed, conversion rate and the ADLPC bit (low power). For lowest power operation the ADLPC bit should be set, the HSC bit should be clear with 1MHz ADC conversion clock speed.
4. 1 LSB = $(V_{REFH} - V_{REFL})/2^N$
5. Input data is 1 kHz sine wave.

FIGURE TBD

Figure 11. Typical TUE vs. ADC conversion rate 12-bit single-ended mode

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FIGURE TBD

Figure 12. Typical ENOB vs. Averaging for 16-bit differential and 16-bit single-ended modes

6.6.1.3 16-bit ADC with PGA operating conditions

Table 25. 16-bit ADC with PGA operating conditions

Symbol	Description	Conditions	Min.	Typ.[1]	Max.	Unit	Notes
V_{DDA}	Supply voltage	Absolute	1.71	—	3.6	V	
V_{REFPGA}	PGA ref voltage		VREFOUT	VREFOUT	VREFOUT	V	2, 3
V_{ADIN}	Input voltage		V_{SSA}	—	V_{DDA}	V	
V_{CM}	Input Common Mode range		V_{SSA}	—	V_{DDA}	V	
R_{PGAD}	Differntial input impedance	Gain = 1, 2, 4, 8 Gain = 16, 32 Gain = 64	— — —	128 64 32	— — —	kΩ	IN+ to IN-[4]
R_{AS}	Analog source resistance		—	100	—	Ω	5
T_S	ADC sampling time		1.25	—	—	µs	6

1. Typical values assume V_{DDA} = 3.0 V, Temp = 25°C, f_{ADCK} = 6 MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
2. ADC must be configured to use the internal voltage reference (VREFOUT)
3. PGA reference connected to the VREFOUT pin. If the user wishes to drive VREFOUT with a voltage other than the output of the VREF module, the VREF module must be disabled.
4. For single ended configurations the input impedence of the driven input is 1/2.
5. The analog source resistance (R_{AS}), external to MCU, should be kept as minimum as possible. Increased R_{AS} causes drop in PGA gain without affecting other performances. This is not dependent on ADC clock frequency.
6. The minimum sampling time is dependent on input signal frequency and ADC mode of operation. A minimum of 1.25µs time should be allowed for F_{in}=4 kHz at 16-bit differential mode. Recommended ADC setting is: ADLSMP=1, ADLSTS=2 at 8 MHz ADC clock.

6.6.1.4 16-bit ADC with PGA characteristics

Table 26. 16-bit ADC with PGA characteristics

Symbol	Description	Conditions	Min.	Typ.[1]	Max.	Unit	Notes
I_{DDA_PGA}	Supply current		—	590	TBD	µA	
I_{DC_PGA}	Input DC current		$\frac{2}{R_{PGAD}}\left(\frac{(V_{REFPGA}\times 0.583)-V_{CM}}{(\text{Gain}+1)}\right)$			A	2
I_{ILKG}	Input Leakage current	PGA disabled	—	TBD	TBD	µA	3

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Table 26. 16-bit ADC with PGA characteristics (continued)

Symbol	Description	Conditions	Min.	Typ.[1]	Max.	Unit	Notes
G	Gain[4]	• PGAG=0 • PGAG=1 • PGAG=2 • PGAG=3 • PGAG=4 • PGAG=5 • PGAG=6	TBD TBD TBD TBD TBD TBD TBD	0.98 1.99 3.97 7.95 15.8 31.4 61.2	TBD TBD TBD TBD TBD TBD TBD		$R_{AS} < 100\Omega$
BW	Input signal bandwidth	• 16-bit modes • < 16-bit modes	— —	— —	4 40	kHz kHz	
PSRR	Power supply rejection ration	Gain=1	TBD	TBD	—	dB	V_{DDA}= 3V ±100mV, f_{VDDA}= 50Hz, 60Hz
CMRR	Common mode rejection ratio	• Gain=1 • Gain=64	TBD TBD	TBD TBD	— —	dB dB	V_{CM}= 500mVpp, f_{VCM}= 50Hz, 100Hz
V_{OFS}	Input offset voltage		—	0.2	TBD	mV	Gain=1, ADC Averaging=32
T_{GSW}	Gain switching settling time		—	—	10	µs	5
dG/dT	Gain drift over temperature	• Gain=1 • Gain=64	— —	TBD TBD	TBD TBD	ppm/°C ppm/°C	0 to 50°C
dV_{OFS}/dT	Offset drift over temperature	Gain=1	—	TBD	TBD	ppm/°C	0 to 50°C, ADC Averaging=32
dG/dV_{DDA}	Gain drift over supply voltage	• Gain=1 • Gain=64	— —	TBD TBD	TBD TBD	%/V %/V	V_{DDA} from 1.71 to 3.6V
E_{IL}	Input leakage error	All modes	$I_{In} \times R_{AS}$			mV	I_{In} = leakage current (refer to the MCU's voltage and current operating ratings)
$V_{PP,DIFF}$	Maximum differential input signal swing		$\left(\frac{(\min(V_X, V_{DDA}-V_X)-0.2)\times 4}{\text{Gain}}\right)$ where $V_X = V_{REFPGA} \times 0.583$			V	6
SNR	Signal-to-noise ratio	• Gain=1 • Gain=64	TBD TBD	83.0 57.5	— —	dB dB	16-bit differential mode, Average=32

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Table 26. 16-bit ADC with PGA characteristics (continued)

Symbol	Description	Conditions	Min.	Typ.[1]	Max.	Unit	Notes
THD	Total harmonic distortion	• Gain=1 • Gain=64	TBD TBD	89.4 90.0	— —	dB dB	16-bit differential mode, Average=32, f_{in}=500Hz
SFDR	Spurious free dynamic range	• Gain=1 • Gain=64	TBD TBD	90.9 77.0	— —	dB dB	16-bit differential mode, Average=32, f_{in}=500Hz
ENOB	Effective number of bits	• Gain=1, Average=4 • Gain=1, Average=8 • Gain=64, Average=4 • Gain=64, Average=8 • Gain=1, Average=32 • Gain=2, Average=32 • Gain=4, Average=32 • Gain=8, Average=32 • Gain=16, Average=32 • Gain=32, Average=32 • Gain=64, Average=32	TBD TBD TBD TBD TBD TBD TBD TBD TBD TBD TBD	12.3 12.7 8.4 8.7 13.3 13.1 12.5 11.8 11.1 10.2 9.3	— — — — — — — — — — —	bits bits bits bits bits bits bits bits bits bits bits	16-bit differential mode, f_{in}=500Hz
SINAD	Signal-to-noise plus distortion ratio	See ENOB	6.02 × ENOB + 1.76			dB	

1. Typical values assume V_{DDA} =3.0V, Temp=25°C, f_{ADCK}=6MHz unless otherwise stated.
2. Between IN+ and IN-. The PGA draws a DC current from the input terminals. The magnitude of the DC current is a strong function if input common mode voltage (V_{CM}) and the PGA gain.
3. This is the input leakage current of the module in addition to the PAD leakage current.
4. Gain = 2^{PGAG}
5. When the PGA gain is changed, it takes some time to settle the output for the ADC to work properly. During a gain switching, a few ADC outputs should be discarded (minimum two data samples, may be more depending on ADC sampling rate and time of the switching).
6. Limit the input signal swing so that the PGA does not saturate during operation. Input signal swing is dependent on the PGA reference voltage and gain setting.

6.6.2 CMP and 6-bit DAC electrical specifications

Table 27. Comparator and 6-bit DAC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
V_{DD}	Supply voltage	1.71	—	3.6	V
I_{DDHS}	Supply current, High-speed mode (EN=1, PMODE=1)	—	—	200	µA

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Table 27. Comparator and 6-bit DAC electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit
I_{DDLS}	Supply current, low-speed mode (EN=1, PMODE=0)	—	—	20	µA
V_{AIN}	Analog input voltage	V_{SS} – 0.3	—	V_{DD}	V
V_{AIO}	Analog input offset voltage	—	—	20	mV
V_H	Analog comparator hysteresis[1]				
	• CR0[HYSTCTR] = 00	—	5	—	mV
	• CR0[HYSTCTR] = 01	—	10	—	mV
	• CR0[HYSTCTR] = 10	—	20	—	mV
	• CR0[HYSTCTR] = 11	—	30	—	mV
V_{CMPOh}	Output high	V_{DD} – 0.5	—	—	V
V_{CMPOl}	Output low	—	—	0.5	V
t_{DHS}	Propagation delay, high-speed mode (EN=1, PMODE=1)	20	50	200	ns
t_{DLS}	Propagation delay, low-speed mode (EN=1, PMODE=0)	120	250	600	ns
	Analog comparator initialization delay[2]	—	—	TBD	ns
I_{DAC6b}	6-bit DAC current adder (enabled)	—	7	—	µA
INL	6-bit DAC integral non-linearity	–0.5	—	0.5	LSB[3]
DNL	6-bit DAC differential non-linearity	–0.3	—	0.3	LSB

1. Typical hysteresis is measured with input voltage range limited to 0.6 to V_{DD}-0.6V.
2. Comparator initialization delay is defined as the time between software writes to change control inputs (Writes to DACEN, VRSEL, PSEL, MSEL, VOSEL) and the comparator output settling to a stable level.
3. 1 LSB = $V_{reference}$/64

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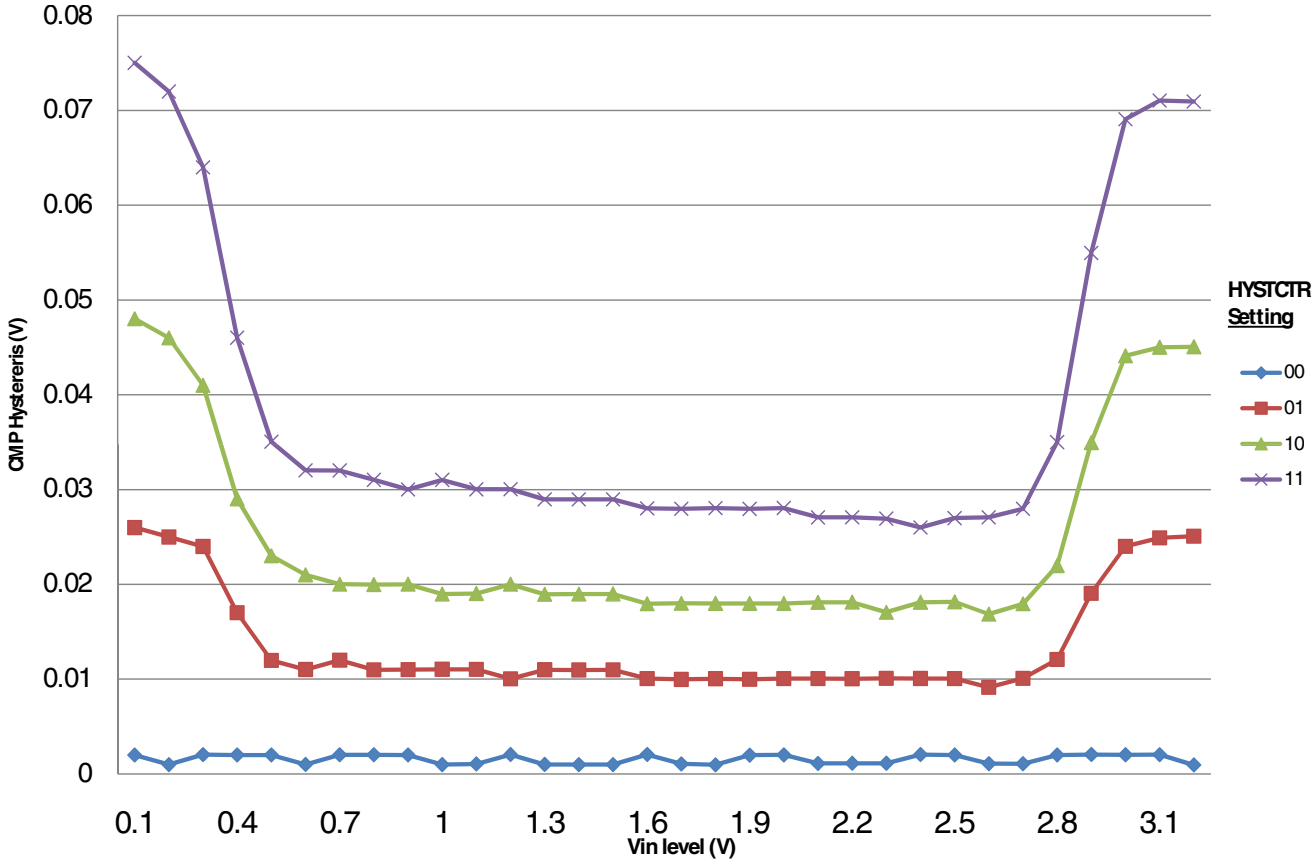

Figure 13. Typical hysteresis vs. Vin level (VDD=3.3V, PMODE=0)

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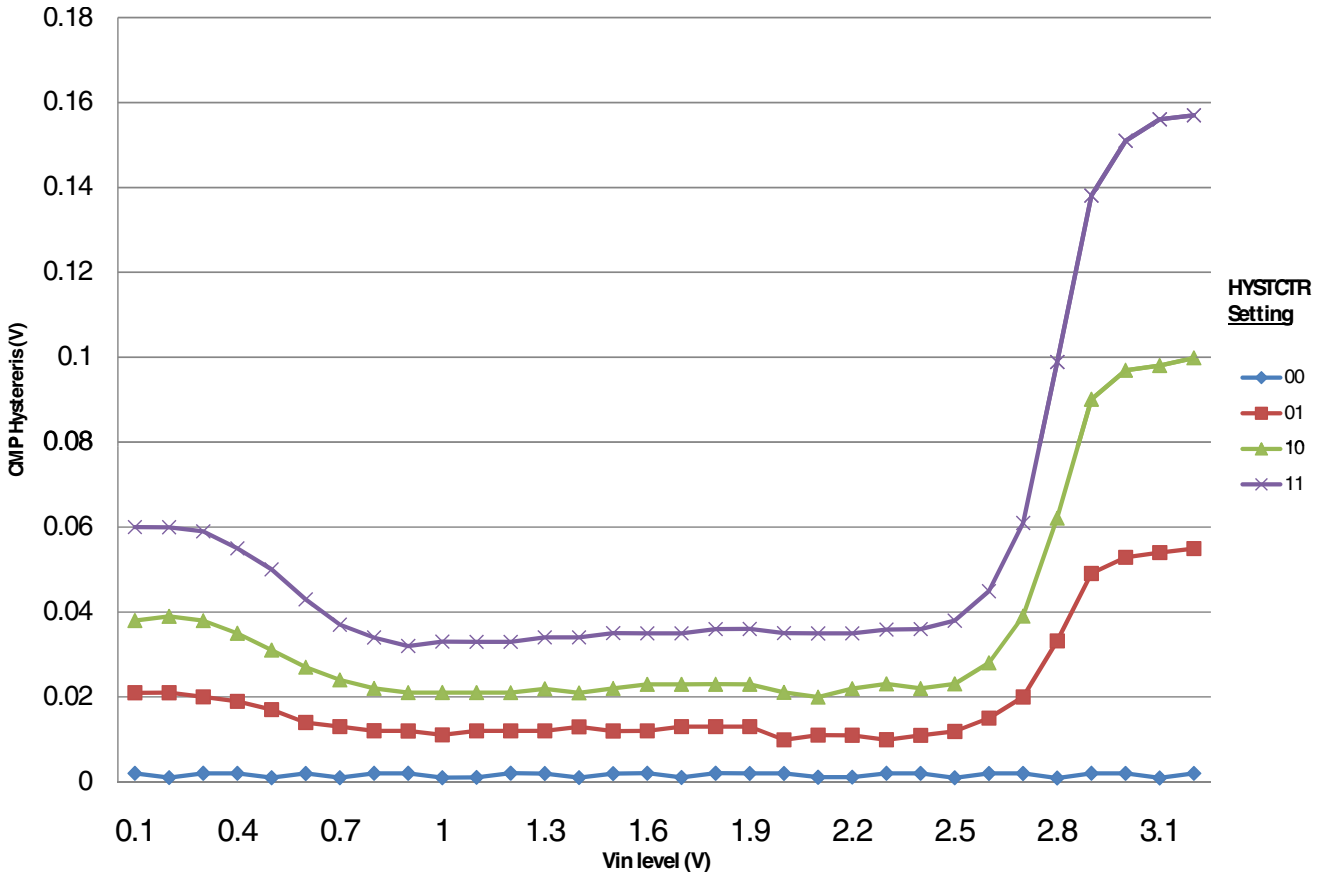

Figure 14. Typical hysteresis vs. Vin level (VDD=3.3V, PMODE=1)

6.6.3 12-bit DAC electrical characteristics

6.6.3.1 12-bit DAC operating requirements

Table 28. 12-bit DAC operating requirements

Symbol	Desciption	Min.	Max.	Unit	Notes
V_{DDA}	Supply voltage	1.71	3.6	V	
V_{DACR}	Reference voltage	1.13	3.6	V	1
T_A	Temperature	–40	105	°C	
C_L	Output load capacitance	—	100	pF	2
I_L	Output load current	—	1	mA	

1. The DAC reference can be selected to be VDDA or the voltage output of the VREF module (VREFO)
2. A small load capacitance (47 pF) can improve the bandwidth performance of the DAC

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6.6.3.2 12-bit DAC operating behaviors

Table 29. 12-bit DAC operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DDA_DACLP}	Supply current — low-power mode	—	—	150	µA	
I_{DDA_DACHP}	Supply current — high-speed mode	—	—	700	µA	
t_{DACLP}	Full-scale settling time (0x080 to 0xF7F) — low-power mode	—	100	200	µs	1
t_{DACHP}	Full-scale settling time (0x080 to 0xF7F) — high-power mode	—	15	30	µs	1
$t_{CCDACLP}$	Code-to-code settling time (0xBF8 to 0xC08) — low-power mode	—	—	5	µs	1
$t_{CCDACHP}$	Code-to-code settling time (0xBF8 to 0xC08) — high-speed mode	1	TBD	—	µs	1
$V_{dacoutl}$	DAC output voltage range low — high-speed mode, no load, DAC set to 0x000	—	100	TBD	mV	
$V_{dacouth}$	DAC output voltage range high — high-speed mode, no load, DAC set to 0xFFF	V_{DACR} –100	—	V_{DACR}	mV	
INL	Integral non-linearity error — high speed mode	—	—	±8	LSB	2
DNL	Differential non-linearity error — V_{DACR} > 2 V	—	—	±1	LSB	3
DNL	Differential non-linearity error — V_{DACR} = VREFO (1.15 V)	—	—	±1	LSB	4
V_{OFFSET}	Offset error	±0.4	—	±0.8	%FSR	5
E_G	Gain error	±0.1	—	±0.6	%FSR	5
PSRR	Power supply rejection ratio, V_{DDA} > = 2.4 V	60		90	dB	
T_{CO}	Temperature coefficient offset voltage	—	TBD	—	µV/C	
T_{GE}	Temperature coefficient gain error	—	TBD	—	ppm of FSR/C	
A_C	Offset aging coefficient	—	—	TBD	µV/yr	
Rop	Output resistance load = 3 kΩ	—	—	250	Ω	
SR	Slew rate -80h→ F7Fh→ 80h • High power (SP_{HP}) • Low power (SP_{LP})	 1.2 0.05	 1.7 0.12	 — —	V/µs	
CT	Channel to channel cross talk	—	—	-80	dB	
BW	3dB bandwidth • High power (SP_{HP}) • Low power (SP_{LP})	 550 40	 — —	 — —	kHz	

1. Settling within ±1 LSB
2. The INL is measured for 0+100mV to V_{DACR}–100 mV
3. The DNL is measured for 0+100 mV to V_{DACR}–100 mV
4. The DNL is measured for 0+100mV to V_{DACR}–100 mV with V_{DDA} > 2.4V

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5. Calculated by a best fit curve from V_{SS}+100 mV to VREF–100 mV

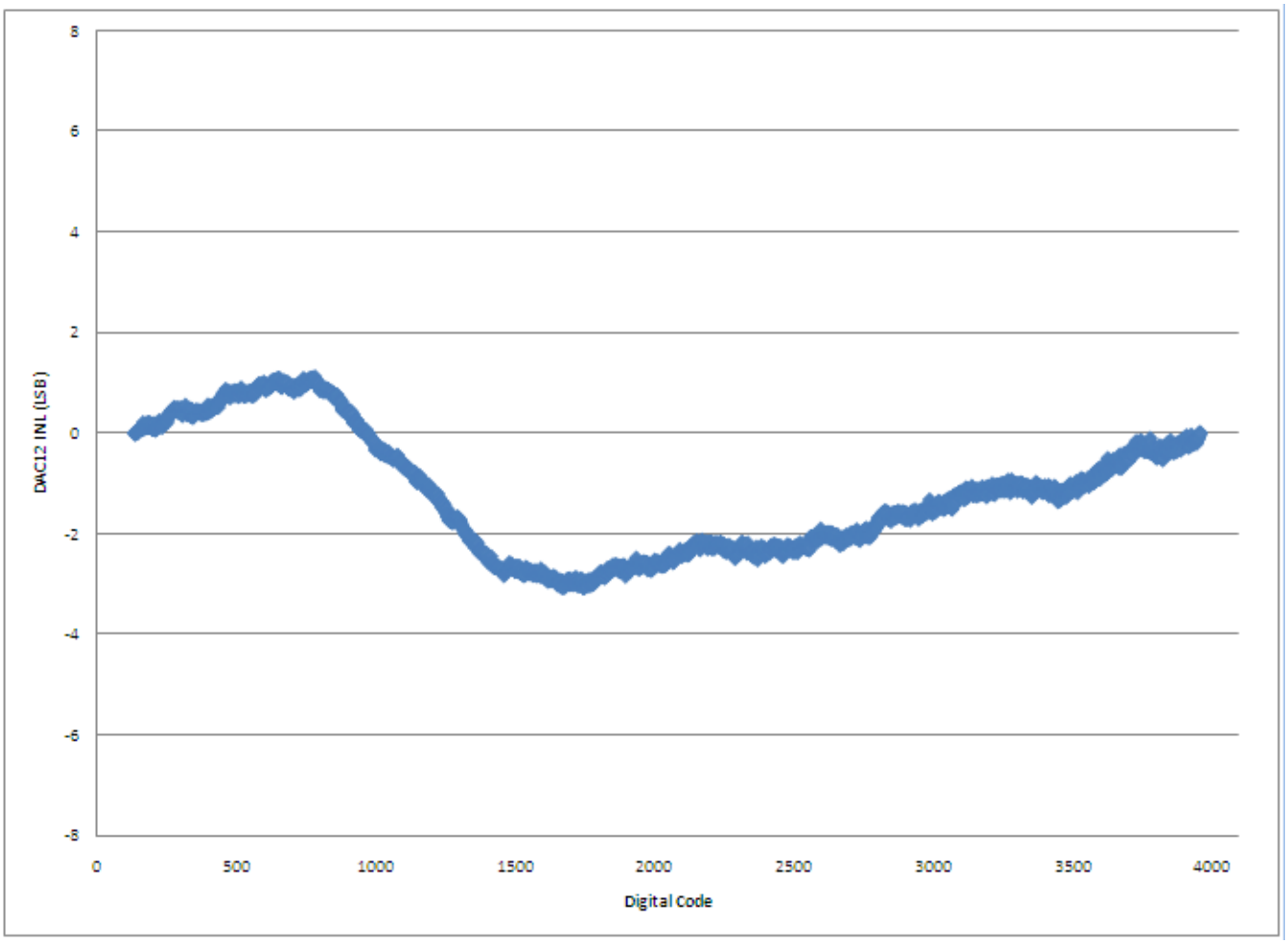

Figure 15. Typical INL error vs. digital code

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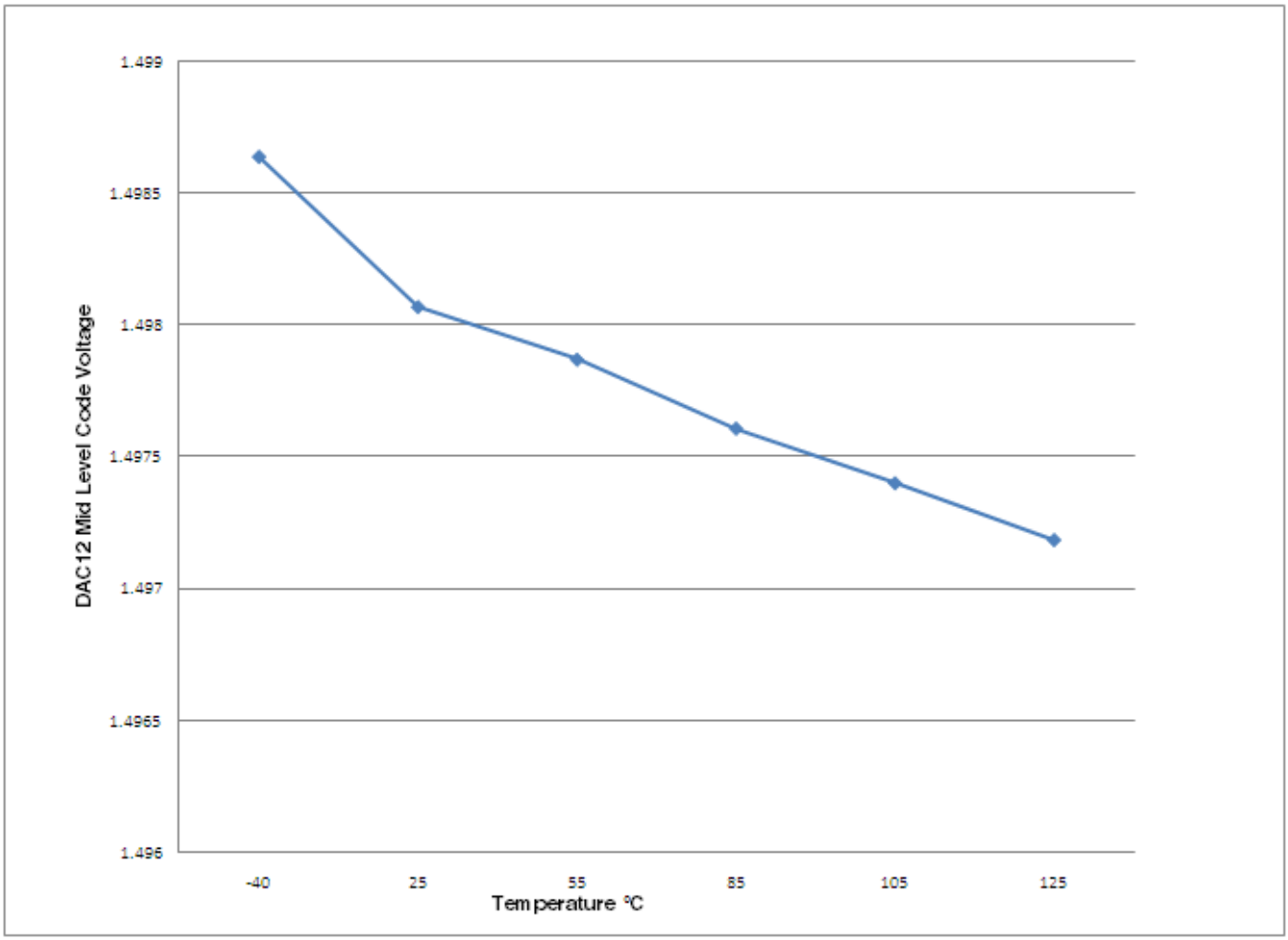

Figure 16. Offset at half scale vs. temperature

6.6.4 Voltage reference electrical specifications

Table 30. VREF full-range operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
V_{DDA}	Supply voltage	1.71	3.6	V	
T_A	Temperature	–40	105	°C	
C_L	Output load capacitance	—	100	nF	

Table 31. VREF full-range operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{out}	Voltage reference output with factory trim at nominal V_{DDA} and temperature=25C	TBD	1.2	TBD	V	

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Table 31. VREF full-range operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{out}	Voltage reference output with factory trim	TBD	—	TBD	V	
V_{out}	Voltage reference output user trim	1.198	—	1.202	V	
V_{step}	Voltage reference trim step	—	0.5	—	mV	
V_{drift}	Temperature drift (Vmax -Vmin across the full temperature range)	—	—	20	mV	See Figure 17
Ac	Aging coefficient	—	—	TBD	ppm/year	
I_{bg}	Bandgap only (MODE_LV = 00) current	—	—	TBD	µA	
I_{tr}	Tight-regulation buffer (MODE_LV =10) current	—	—	1.1	mA	
	Load regulation (MODE_LV = 10) current = ±1.0mA	—	—	TBD	V	
T_{stup}	Buffer startup time	—	—	100	µs	
DC	Line regulation (power supply rejection)	—	—	TBD	mV	
		–60	—	TBD	dB	

Table 32. VREF limited-range operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
T_A	Temperature	0	50	°C	

Table 33. VREF limited-range operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
V_{out}	Voltage reference output with factory trim	TBD	TBD	V	

TBD

Figure 17. Typical output vs.temperature

TBD

Figure 18. Typical output vs. VDD

6.7 Timers

See General switching specifications.

6.8 Communication interfaces

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6.8.1 CAN switching specifications

See General switching specifications.

6.8.2 DSPI switching specifications (low-speed mode)

The DMA Serial Peripheral Interface (DSPI) provides a synchronous serial bus with master and slave operations. Many of the transfer attributes are programmable. The tables below provides DSPI timing characteristics for classic SPI timing modes. Refer to the DSPI chapter of the Reference Manual for information on the modified transfer formats used for communicating with slower peripheral devices.

Table 34. Master mode DSPI timing (low-speed mode)

Num	Description	Min.	Max.	Unit	Notes
	Operating voltage	1.71	3.6	V	1
	Frequency of operation	—	12.5	MHz	
DS1	DSPI_SCK output cycle time	4 x t_{BCLK}	—	ns	
DS2	DSPI_SCK output high/low time	(t_{SCK}/2) - 4	($t_{SCK/2)}$ + 4	ns	
DS3	DSPI_PCS*n* to DSPI_SCK output valid	(t_{SCK}/2) - 4	—	ns	
DS4	DSPI_SCK to DSPI_PCS*n* output hold	(t_{SCK}/2) - 4	—	ns	
DS5	DSPI_SCK to DSPI_SOUT valid	—	10	ns	
DS6	DSPI_SCK to DSPI_SOUT invalid	-2	—	ns	
DS7	DSPI_SIN to DSPI_SCK input setup	15	—	ns	
DS8	DSPI_SCK to DSPI_SIN input hold	0	—	ns	

1. The DSPI module can operate across the entire operating voltage for the processor, but to run across the full voltage range the maximum frequency of operation is reduced.

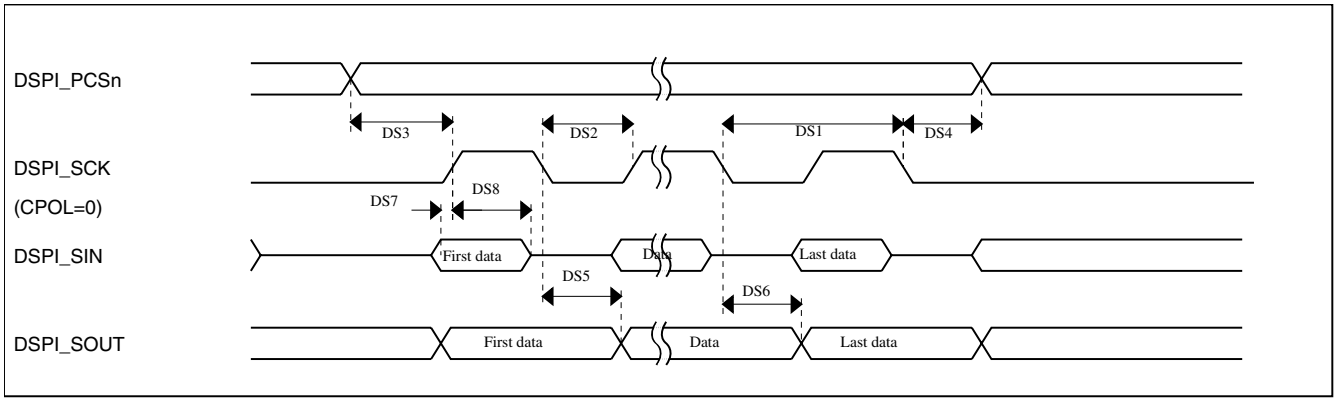

Figure 19. DSPI classic SPI timing — master mode

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Table 35. Slave mode DSPI timing (low-speed mode)

Num	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
	Frequency of operation	—	6.25	MHz
DS9	DSPI_SCK input cycle time	8 x t_{BCLK}	—	ns
DS10	DSPI_SCK input high/low time	(t_{SCK}/2) - 4	($t_{SCK/2)}$ + 4	ns
DS11	DSPI_SCK to DSPI_SOUT valid	—	20	ns
DS12	DSPI_SCK to DSPI_SOUT invalid	0	—	ns
DS13	DSPI_SIN to DSPI_SCK input setup	5	—	ns
DS14	DSPI_SCK to DSIP_SIN input hold	15	—	ns
DS15	$\overline{\text{DSPI\_SS}}$ active to DSPI_SOUT driven	—	15	ns
DS16	$\overline{\text{DSPI\_SS}}$ inactive to DSPI_SOUT not driven	—	15	ns

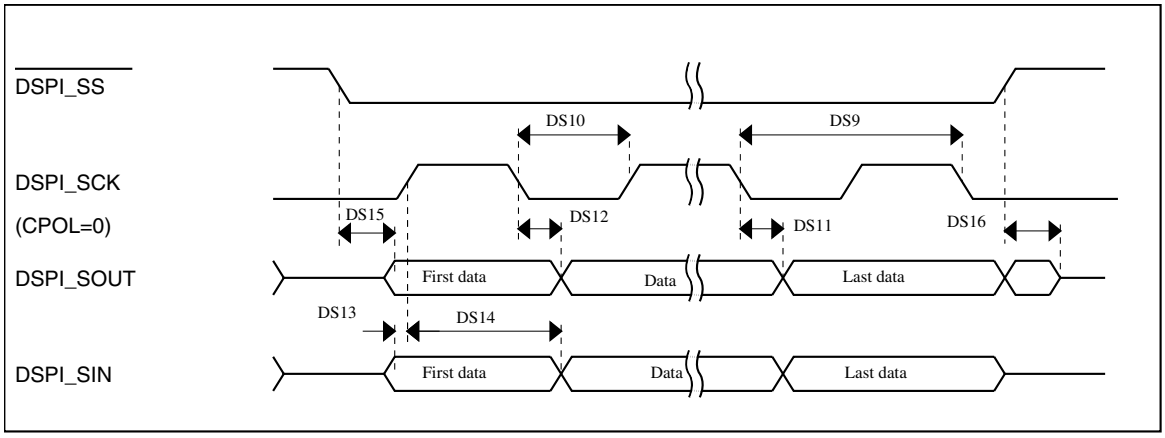

Figure 20. DSPI classic SPI timing — slave mode

6.8.3 DSPI switching specifications (high-speed mode)

The DMA Serial Peripheral Interface (DSPI) provides a synchronous serial bus with master and slave operations. Many of the transfer attributes are programmable. The tables below provide DSPI timing characteristics for classic SPI timing modes. Refer to the DSPI chapter of the Reference Manual for information on the modified transfer formats used for communicating with slower peripheral devices.

Table 36. Master mode DSPI timing (high-speed mode)

Num	Description	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
	Frequency of operation	—	25	MHz

Table continues on the next page...

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Table 36. Master mode DSPI timing (high-speed mode) (continued)

Num	Description	Min.	Max.	Unit
DS1	DSPI_SCK output cycle time	2 x t_{BCLK}	—	ns
DS2	DSPI_SCK output high/low time	(t_{SCK}/2) – 2	(t_{SCK}/2) + 2	ns
DS3	DSPI_PCS*n* to DSPI_SCK output valid	(t_{SCK}/2) – 2	—	ns
DS4	DSPI_SCK to DSPI_PCS*n* output hold	(t_{SCK}/2) – 2	—	ns
DS5	DSPI_SCK to DSPI_SOUT valid	—	8.5	ns
DS6	DSPI_SCK to DSPI_SOUT invalid	–2	—	ns
DS7	DSPI_SIN to DSPI_SCK input setup	TBD	—	ns
DS8	DSPI_SCK to DSPI_SIN input hold	0	—	ns

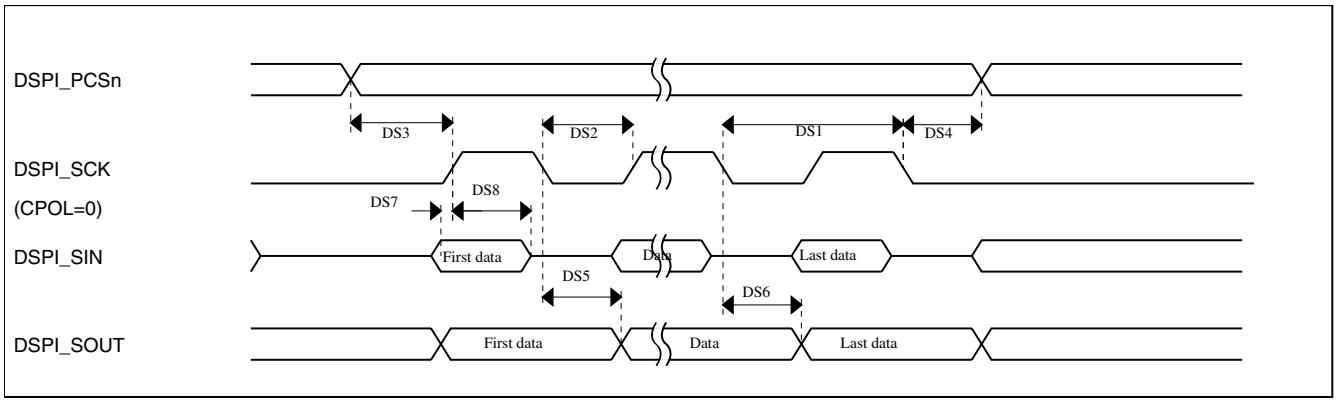

Figure 21. DSPI classic SPI timing — master mode

Table 37. Slave mode DSPI timing (high-speed mode)

Num	Description	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
	Frequency of operation		12.5	MHz
DS9	DSPI_SCK input cycle time	4 x t_{BCLK}	—	ns
DS10	DSPI_SCK input high/low time	(t_{SCK}/2) – 2	(t_{SCK}/2 + 2	ns
DS11	DSPI_SCK to DSPI_SOUT valid	—	TBD	ns
DS12	DSPI_SCK to DSPI_SOUT invalid	0	—	ns
DS13	DSPI_SIN to DSPI_SCK input setup	2	—	ns
DS14	DSPI_SCK to DSIP_SIN input hold	7	—	ns
DS15	$\overline{\text{DSPI\_SS}}$ active to DSPI_SOUT driven	—	14	ns
DS16	$\overline{\text{DSPI\_SS}}$ inactive to DSPI_SOUT not driven	—	14	ns

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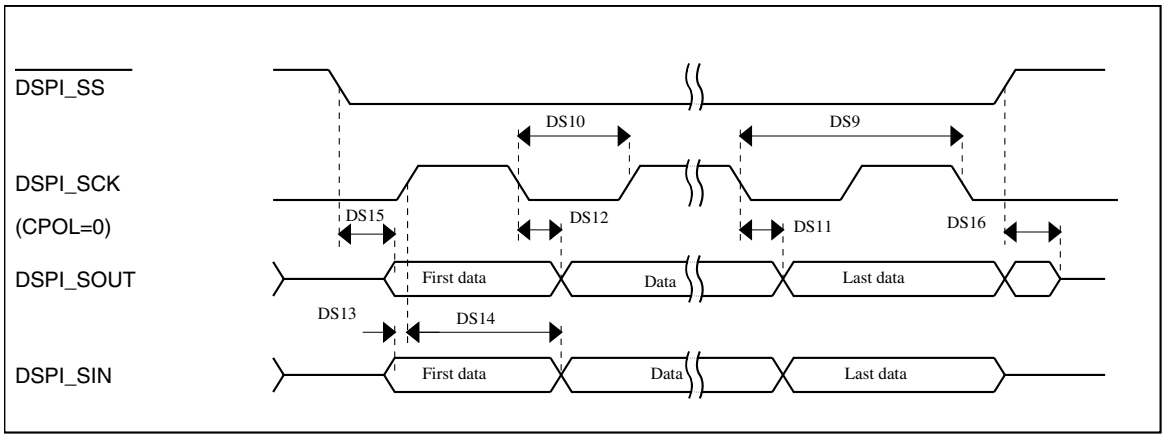

Figure 22. DSPI classic SPI timing — slave mode

6.8.4 I²C switching specifications

See General switching specifications.

6.8.5 UART switching specifications

See General switching specifications.

6.8.6 SDHC specifications

The following timing specs are defined at the chip I/O pin and must be translated appropriately to arrive at timing specs/constraints for the physical interface.

Table 38. SDHC switching specifications

Num	Symbol	Description	Min.	Max.	Unit
		Operating voltage	2.7	3.6	V
Card input clock					
SD1	fpp	Clock frequency (low speed)	0	400	kHz
	fpp	Clock frequency (SD\SDIO full speed)	0	25	MHz
	fpp	Clock frequency (MMC full speed)	0	20	MHz
	f_{OD}	Clock frequency (identification mode)	0	400	kHz
SD2	t_{WL}	Clock low time	7	—	ns
SD3	t_{WH}	Clock high time	7	—	ns
SD4	t_{TLH}	Clock rise time	—	3	ns

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Table 38. SDHC switching specifications (continued)

Num	Symbol	Description	Min.	Max.	Unit
SD5	t_{THL}	Clock fall time	—	3	ns
SDHC output / card inputs SDHC_CMD, SDHC_DAT (reference to SDHC_CLK)					
SD6	t_{OD}	SDHC output delay (output valid)	-5	6.5	ns
SDHC input / card inputs SDHC_CMD, SDHC_DAT (reference to SDHC_CLK)					
SD7	t_{THL}	SDHC input setup time	5	—	ns
SD8	t_{THL}	SDHC input hold time	0	—	ns

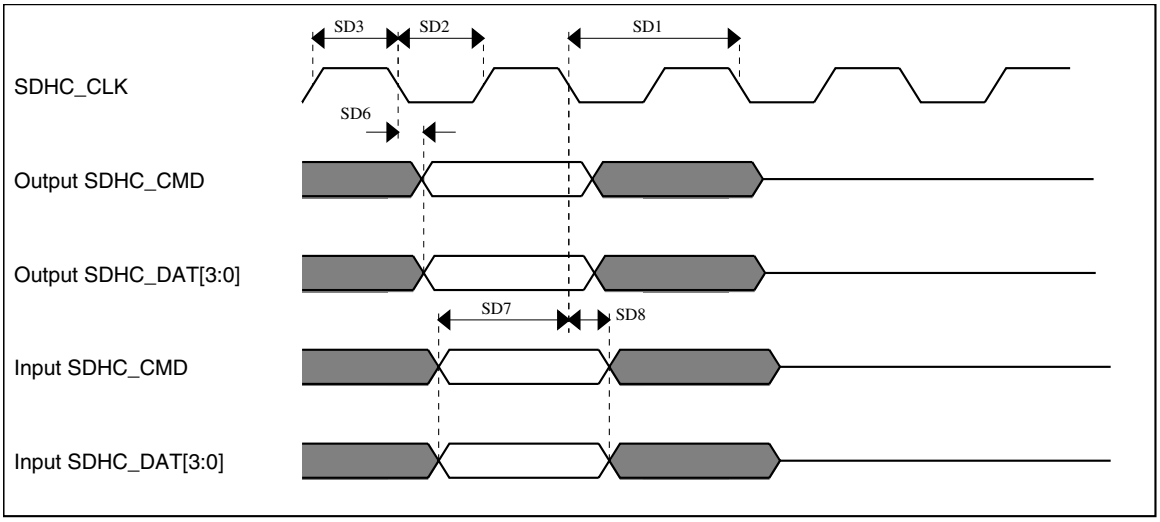

Figure 23. SDHC timing

6.8.7 I²S switching specifications

This section provides the AC timings for the I²S in master (clocks driven) and slave modes (clocks input). All timings are given for non-inverted serial clock polarity (TCR[TSCKP] = 0, RCR[RSCKP] = 0) and a non-inverted frame sync (TCR[TFSI] = 0, RCR[RFSI] = 0). If the polarity of the clock and/or the frame sync have been inverted, all the timings remain valid by inverting the clock signal (I2S_BCLK) and/or the frame sync (I2S_FS) shown in the figures below.

Table 39. I²S master mode timing

Num	Description	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
S1	I2S_MCLK cycle time	2 x t_{SYS}		ns

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Table 39. I²S master mode timing (continued)

Num	Description	Min.	Max.	Unit
S2	I2S_MCLK pulse width high/low	45%	55%	MCLK period
S3	I2S_BCLK cycle time	5 x t_{SYS}	—	ns
S4	I2S_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_BCLK to I2S_FS output valid	—	15	ns
S6	I2S_BCLK to I2S_FS output invalid	-2.5	—	ns
S7	I2S_BCLK to I2S_TXD valid	—	15	ns
S8	I2S_BCLK to I2S_TXD invalid	-3	—	ns
S9	I2S_RXD/I2S_FS input setup before I2S_BCLK	20	—	ns
S10	I2S_RXD/I2S_FS input hold after I2S_BCLK	0	—	ns

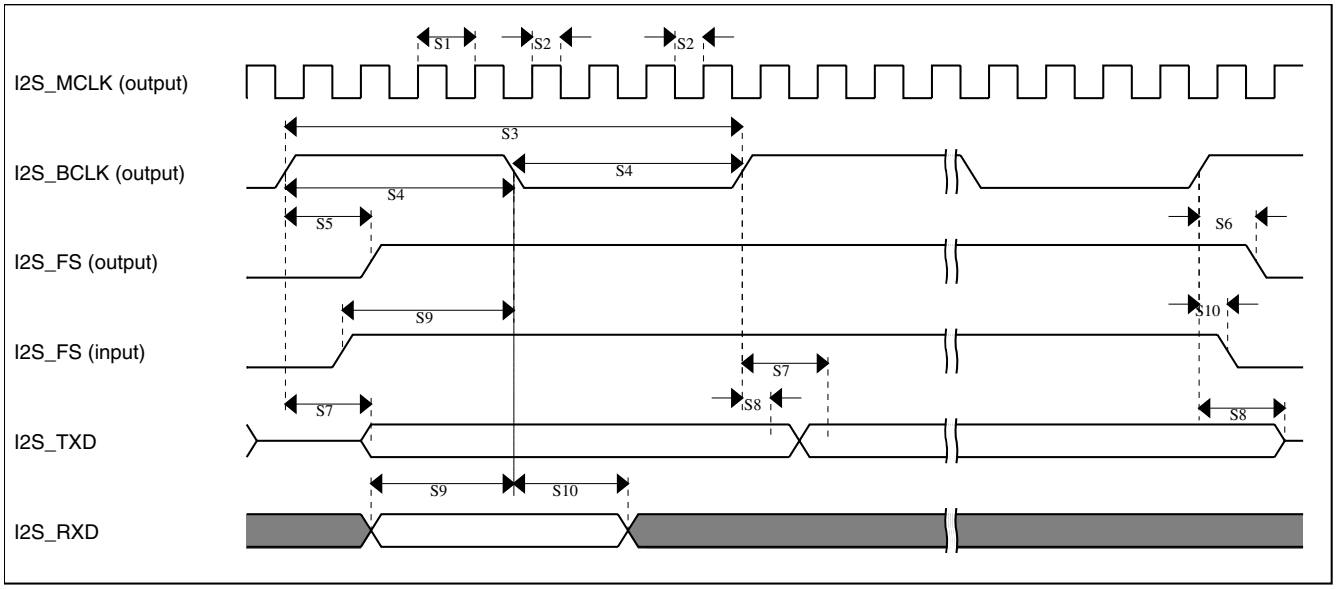

Figure 24. I²S timing — master mode

Table 40. I²S slave mode timing

Num	Description	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
S11	I2S_BCLK cycle time (input)	8 x t_{SYS}	—	ns
S12	I2S_BCLK pulse width high/low (input)	45%	55%	MCLK period
S13	I2S_FS input setup before I2S_BCLK	10	—	ns
S14	I2S_FS input hold after I2S_BCLK	3	—	ns
S15	I2S_BCLK to I2S_TXD/I2S_FS output valid	—	20	ns
S16	I2S_BCLK to I2S_TXD/I2S_FS output invalid	0	—	ns
S17	I2S_RXD setup before I2S_BCLK	10	—	ns

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Table 40. I²S slave mode timing (continued)

Num	Description	Min.	Max.	Unit
S18	I2S_RXD hold after I2S_BCLK	2	—	ns

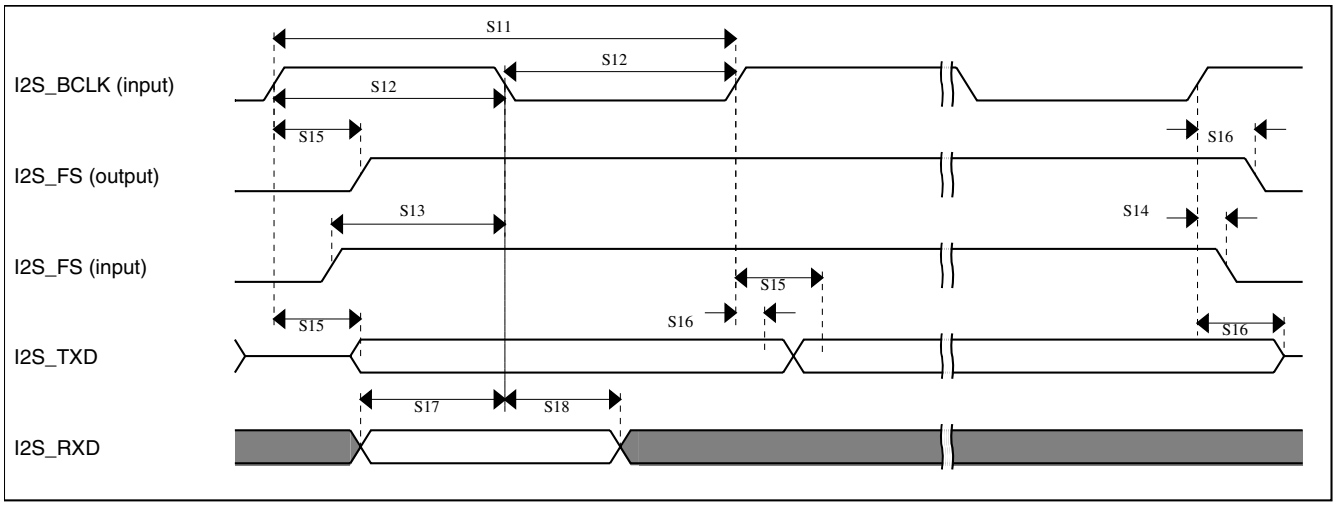

Figure 25. I²S timing — slave modes

6.9 Human-machine interfaces (HMI)

6.9.1 TSI electrical specifications

Table 41. TSI electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{DDTSI}	Operating voltage	1.71	—	3.6	V	
C_{ELE}	Target electrode capacitance range	1	20	500	pF	1
f_{REFmax}	Reference oscillator frequency	—	5.5	TBD	MHz	
f_{ELEmax}	Electrode oscillator frequency	—	0.5	TBD	MHz	
C_{REF}	Internal reference capacitor	TBD	1	TBD	pF	
V_{DELTA}	Oscillator delta voltage	TBD	600	TBD	mV	
I_{REF}	Reference oscillator current source base current	TBD	1	TBD	µA	2
I_{ELE}	Electrode oscillator current source base current	TBD	1	TBD	µA	2
Pres5	Electrode capacitance measurement precision	—	TBD	TBD	%	3
Pres20	Electrode capacitance measurement precision	—	TBD	TBD	%	4
Pres100	Electrode capacitance measurement precision	—	TBD	TBD	%	5

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Table 41. TSI electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
MaxSens20	Maximum sensitivity @ 20 pF electrode	0.003	0.25	—	fF/count	6
MaxSens	Maximum sensitivity	0.003	—	—	fF/count	7
Res	Resolution	—	—	16	bits	
T_{Con20}	Response time @ 20 pF	8	15	25	µs	8
I_{TSI_RUN}	Current added in run mode	—	TBD	—	µA	
I_{TSI_LP}	Low power mode current adder	—	1	TBD	µA	

1. The TSI module is functional with capacitance values outside this range. However, optimal performance is not guaranteed.
2. The programmable current source value is generated by multiplying the SCANC[REFCHRG] value and the base current.
3. Measured with a 5 pF electrode, reference oscillator frequency of 10 MHz, PS = 128, NSCN = 8; Iext = 16.
4. Measured with a 20 pF electrode, reference oscillator frequency of 10 MHz, PS = 128, NSCN = 2; Iext = 16.
5. Measured with a 20 pF electrode, reference oscillator frequency of 10 MHz, PS = 16, NSCN = 3; Iext = 16.
6. Measured with a 20 pF electrode, reference oscillator frequency of ~5 MHz (I_{REF} = 5 µA, REFCHRG = 4), PS = 128, NSCN = 2; Iext = 16 (EXTCHRG = 15).
7. Typical value depends on the configuration used.
8. Time to do one complete measurement of the electrode. Sensitivity resolution of 0.0133 pF, PS = 0, NSCN = 0, 1 electrode, DELVOL = 2, EXTCHRG = 15.

6.9.2 LCD electrical characteristics

Table 42. LCD electricals

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f_{Frame}	LCD frame frequency	28	30	58	Hz	
C_{LCD}	LCD charge pump capacitance — nominal value	—	100	—	nF	1
C_{BYLCD}	LCD bypass capacitance — nominal value	—	100	—	nF	1
C_{Glass}	LCD glass capacitance	—	2000	8000	pF	
V_{IREG}	V_{IREG} — HREFSEL = 0					2
	• HREFSEL = 0	0.89	1.00	1.15	V	
	• HREFSEL = 1	1.49	1.67	1.85	V	
Δ_{RTRIM}	V_{IREG} TRIM resolution	3.0	—	—	% V_{IREG}	
—	V_{IREG} ripple					
	• HREFSEL = 0	—	—	30	mV	
	• HREFSEL = 1	—	—	50	mV	
I_{VIREG}	V_{IREG} current adder — RVEN = 1	—	1	—	µA	3
I_{RBIAS}	RBIAS current adder					3
	• HREFSEL = 0	—	10	—	µA	
	• HREFSEL = 1	—	1	—	µA	

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Table 42. LCD electricals (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
R_{RBIAS}	RBIAS resistor values					
	• LADJ = 00 or 01 — Low load (LCD glass capacitance ≤ 2000 pF)	—	0.28	—	MΩ	
	• LADJ = 10 or 11 — High load (LCD glass capacitance ≤ 8000 pF)	—	2.98	—	MΩ	
VLL2	VLL2 voltage					
	• HREFSEL = 0	2.0 – 5%	2.0	—	V	
	• HREFSEL = 1	3.3 – 5%	3.3	—	V	
VLL3	VLL3 voltage					
	• HREFSEL = 0	3.0 – 5%	3.0	—	V	
	• HREFSEL = 1	5 – 5%	5	—	V	

1. The actual value used could vary with tolerance.
2. V_{IREG} maximum should never be externally driven to any level other than V_{DD} - 0.15 V
3. 2000 pF load LCD, 32 Hz frame frequency

7 Dimensions

7.1 Obtaining package dimensions

Package dimensions are provided in package drawings.

To find a package drawing, go to http://www.freescale.com and perform a keyword search for the drawing's document number:

If you want the drawing for this package	Then use this document number
80-pin LQFP	98ASS23174W
81-pin MAPBGA	98ASA10631D

8 Pinout

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8.1 K30 Signal Multiplexing and Pin Assignments

The following table shows the signals available on each pin and the locations of these pins on the devices supported by this document. The Port Control Module is responsible for selecting which ALT functionality is available on each pin.

NOTE

The 81-pin ballmap assignments are currently being developed. The • in the entries in this package column indicate which signals are present on the package.

81 MAP BGA	80 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
•	1	PTE0	ADC1_SE4a	ADC1_SE4a	PTE0	SPI1_PCS1	UART1_TX	SDHC0_D1		I2C1_SDA		
•	2	PTE1	ADC1_SE5a	ADC1_SE5a	PTE1	SPI1_SOUT	UART1_RX	SDHC0_D0		I2C1_SCL		
•	3	PTE2	ADC1_SE6a	ADC1_SE6a	PTE2	SPI1_SCK	UART1_CTS_b	SDHC0_DCLK				
•	4	PTE3	ADC1_SE7a	ADC1_SE7a	PTE3	SPI1_SIN	UART1_RTS_b	SDHC0_CMD				
•	5	PTE4	DISABLED		PTE4	SPI1_PCS0	UART3_TX	SDHC0_D3				
•	6	PTE5	DISABLED		PTE5	SPI1_PCS2	UART3_RX	SDHC0_D2				
•	7	VDD	VDD	VDD								
•	8	VSS	VSS	VSS								
•	9	PTE16	ADC0_SE4a	ADC0_SE4a	PTE16	SPI0_PCS0	UART2_TX	FTM_CLKIN0		FTM0_FLT3		
•	10	PTE17	ADC0_SE5a	ADC0_SE5a	PTE17	SPI0_SCK	UART2_RX	FTM_CLKIN1		LPT00_ALT3		
•	11	PTE18	ADC0_SE6a	ADC0_SE6a	PTE18	SPI0_SOUT	UART2_CTS_b	I2C0_SDA				
•	12	PTE19	ADC0_SE7a	ADC0_SE7a	PTE19	SPI0_SIN	UART2_RTS_b	I2C0_SCL				
•	13	PGA0_DP/ ADC0_DP0/ ADC1_DP3	PGA0_DP/ ADC0_DP0/ ADC1_DP3	PGA0_DP/ ADC0_DP0/ ADC1_DP3								
•	14	PGA0_DM/ ADC0_DM0/ ADC1_DM3	PGA0_DM/ ADC0_DM0/ ADC1_DM3	PGA0_DM/ ADC0_DM0/ ADC1_DM3								
•	15	PGA1_DP/ ADC1_DP0/ ADC0_DP3	PGA1_DP/ ADC1_DP0/ ADC0_DP3	PGA1_DP/ ADC1_DP0/ ADC0_DP3								
•	16	PGA1_DM/ ADC1_DM0/ ADC0_DM3	PGA1_DM/ ADC1_DM0/ ADC0_DM3	PGA1_DM/ ADC1_DM0/ ADC0_DM3								
•	17	VDDA	VDDA	VDDA								
•	18	VREFH	VREFH	VREFH								
•	19	VREFL	VREFL	VREFL								

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81 MAP BGA	80 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
•	20	VSSA	VSSA	VSSA								
•	21	VREF_OUT/ CMP1_IN5/ CMP0_IN5/ ADC1_SE18	VREF_OUT	VREF_OUT/ CMP1_IN5/ CMP0_IN5/ ADC1_SE18								
•	22	DAC0_OUT/ CMP1_IN3/ ADC0_SE23	DAC0_OUT	DAC0_OUT/ CMP1_IN3/ ADC0_SE23								
•	23	XTAL32	XTAL32	XTAL32								
•	24	EXTAL32	EXTAL32	EXTAL32								
•	25	VBAT	VBAT	VBAT								
•	26	PTA0	JTAG_TCLK/ SWD_CLK/ EZP_CLK	TSI0_CH1	PTA0	UART0_CTS_b	FTM0_CH5				JTAG_TCLK/ SWD_CLK	EZP_CLK
•	27	PTA1	JTAG_TDI/ EZP_DI	TSI0_CH2	PTA1	UART0_RX	FTM0_CH6				JTAG_TDI	EZP_DI
•	28	PTA2	JTAG_TDO/ TRACE_SWO/EZP_DO	TSI0_CH3	PTA2	UART0_TX	FTM0_CH7				JTAG_TDO/ TRACE_SWO	EZP_DO
•	29	PTA3	JTAG_TMS/ SWD_DIO	TSI0_CH4	PTA3	UART0_RTS_b	FTM0_CH0				JTAG_TMS/ SWD_DIO	
•	30	PTA4	NMI_b/ EZP_CS_b	TSI0_CH5	PTA4		FTM0_CH1				NMI_b	EZP_CS_b
•	31	PTA5	DISABLED		PTA5		FTM0_CH2		CMP2_OUT	I2S0_RX_BCLK	JTAG_TRST	
•	32	PTA12	CMP2_IN0	CMP2_IN0	PTA12	CAN0_TX	FTM1_CH0			I2S0_TXD	FTM1_QD_PHA	
•	33	PTA13	CMP2_IN1	CMP2_IN1	PTA13	CAN0_RX	FTM1_CH1			I2S0_TX_FS	FTM1_QD_PHB	
•	34	PTA14	DISABLED		PTA14	SPI0_PCS0	UART0_TX			I2S0_TX_BCLK		
•	35	PTA15	DISABLED		PTA15	SPI0_SCK	UART0_RX			I2S0_RXD		
•	36	PTA16	DISABLED		PTA16	SPI0_SOUT	UART0_CTS_b			I2S0_RX_FS		
•	37	PTA17	ADC1_SE17	ADC1_SE17	PTA17	SPI0_SIN	UART0_RTS_b			I2S0_MCLK	I2S0_CLKIN	
•	38	VDD	VDD	VDD								
•	39	VSS	VSS	VSS								
•	40	PTA18	EXTAL	EXTAL	PTA18		FTM0_FLT2	FTM_CLKIN0				
•	41	PTA19	XTAL	XTAL	PTA19		FTM1_FLT0	FTM_CLKIN1		LPT0_ALT1		
•	42	RESET_b	RESET_b	RESET_b								

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81 MAP BGA	80 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
•	43	PTB0	LCD_P0/ ADC0_SE8/ ADC1_SE8/ TSI0_CH0	LCD_P0/ ADC0_SE8/ ADC1_SE8/ TSI0_CH0	PTB0	I2C0_SCL	FTM1_CH0			FTM1_QD_ PHA	LCD_P0	
•	44	PTB1	LCD_P1/ ADC0_SE9/ ADC1_SE9/ TSI0_CH6	LCD_P1/ ADC0_SE9/ ADC1_SE9/ TSI0_CH6	PTB1	I2C0_SDA	FTM1_CH1			FTM1_QD_ PHB	LCD_P1	
•	45	PTB2	LCD_P2/ ADC0_SE1 2/TSI0_CH7	LCD_P2/ ADC0_SE1 2/TSI0_CH7	PTB2	I2C0_SCL	UART0_RT S_b			FTM0_FLT3	LCD_P2	
•	46	PTB3	LCD_P3/ ADC0_SE1 3/TSI0_CH8	LCD_P3/ ADC0_SE1 3/TSI0_CH8	PTB3	I2C0_SDA	UART0_CT S_b			FTM0_FLT0	LCD_P3	
•	47	PTB8	LCD_P8	LCD_P8	PTB8		UART3_RT S_b				LCD_P8	
•	48	PTB9	LCD_P9	LCD_P9	PTB9	SPI1_PCS1	UART3_CT S_b				LCD_P9	
•	49	PTB10	LCD_P10/ ADC1_SE1 4	LCD_P10/ ADC1_SE1 4	PTB10	SPI1_PCS0	UART3_RX			FTM0_FLT1	LCD_P10	
•	50	PTB11	LCD_P11/ ADC1_SE1 5	LCD_P11/ ADC1_SE1 5	PTB11	SPI1_SCK	UART3_TX			FTM0_FLT2	LCD_P11	
•	51	PTB16	LCD_P12/ TSI0_CH9	LCD_P12/ TSI0_CH9	PTB16	SPI1_SOUT	UART0_RX			EWM_IN	LCD_P12	
•	52	PTB17	LCD_P13/ TSI0_CH10	LCD_P13/ TSI0_CH10	PTB17	SPI1_SIN	UART0_TX			EWM_OUT _b	LCD_P13	
•	53	PTB18	LCD_P14/ TSI0_CH11	LCD_P14/ TSI0_CH11	PTB18	CAN0_TX	FTM2_CH0	I2S0_TX_B CLK		FTM2_QD_ PHA	LCD_P14	
•	54	PTB19	LCD_P15/ TSI0_CH12	LCD_P15/ TSI0_CH12	PTB19	CAN0_RX	FTM2_CH1	I2S0_TX_F S		FTM2_QD_ PHB	LCD_P15	
•	55	PTC0	LCD_P20/ ADC0_SE1 4/ TSI0_CH13	LCD_P20/ ADC0_SE1 4/ TSI0_CH13	PTC0	SPI0_PCS4	PDB0_EXT RG	I2S0_TXD			LCD_P20	
•	56	PTC1	LCD_P21/ ADC0_SE1 5/ TSI0_CH14	LCD_P21/ ADC0_SE1 5/ TSI0_CH14	PTC1	SPI0_PCS3	UART1_RT S_b	FTM0_CH0			LCD_P21	
•	57	PTC2	LCD_P22/ ADC0_SE4 b/ CMP1_IN0/ TSI0_CH15	LCD_P22/ ADC0_SE4 b/ CMP1_IN0/ TSI0_CH15	PTC2	SPI0_PCS2	UART1_CT S_b	FTM0_CH1			LCD_P22	
•	58	PTC3	LCD_P23/ CMP1_IN1	LCD_P23/ CMP1_IN1	PTC3	SPI0_PCS1	UART1_RX	FTM0_CH2			LCD_P23	
•	59	VSS	VSS	VSS								
•	60	VLL3	VLL3	VLL3								

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81 MAP BGA	80 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
•	61	VLL2	VLL2	VLL2								
•	62	VLL1	VLL1	VLL1								
•	63	VCAP2	VCAP2	VCAP2								
•	64	VCAP1	VCAP1	VCAP1								
•	65	PTC4	LCD_P24	LCD_P24	PTC4	SPI0_PCS0	UART1_TX	FTM0_CH3		CMP1_OUT	LCD_P24	
•	66	PTC5	LCD_P25	LCD_P25	PTC5	SPI0_SCK		LPT0_ALT2		CMP0_OUT	LCD_P25	
•	67	PTC6	LCD_P26/ CMP0_IN0	LCD_P26/ CMP0_IN0	PTC6	SPI0_SOUT	PDB0_EXTRG				LCD_P26	
•	68	PTC7	LCD_P27/ CMP0_IN1	LCD_P27/ CMP0_IN1	PTC7	SPI0_SIN					LCD_P27	
•	69	PTC8	LCD_P28/ ADC1_SE4b/ CMP0_IN2	LCD_P28/ ADC1_SE4b/ CMP0_IN2	PTC8		I2S0_MCLK	I2S0_CLKIN			LCD_P28	
•	70	PTC9	LCD_P29/ ADC1_SE5b/ CMP0_IN3	LCD_P29/ ADC1_SE5b/ CMP0_IN3	PTC9			I2S0_RX_BCLK		FTM2_FLT0	LCD_P29	
•	71	PTC10	LCD_P30/ ADC1_SE6b/ CMP0_IN4	LCD_P30/ ADC1_SE6b/ CMP0_IN4	PTC10	I2C1_SCL		I2S0_RX_FS			LCD_P30	
•	72	PTC11	LCD_P31/ ADC1_SE7b	LCD_P31/ ADC1_SE7b	PTC11	I2C1_SDA		I2S0_RXD			LCD_P31	
•	73	PTD0	LCD_P40	LCD_P40	PTD0	SPI0_PCS0	UART2_RTS_b				LCD_P40	
•	74	PTD1	LCD_P41/ ADC0_SE5b	LCD_P41/ ADC0_SE5b	PTD1	SPI0_SCK	UART2_CTS_b				LCD_P41	
•	75	PTD2	LCD_P42	LCD_P42	PTD2	SPI0_SOUT	UART2_RX				LCD_P42	
•	76	PTD3	LCD_P43	LCD_P43	PTD3	SPI0_SIN	UART2_TX				LCD_P43	
•	77	PTD4	LCD_P44	LCD_P44	PTD4	SPI0_PCS1	UART0_RTS_b	FTM0_CH4		EWM_IN	LCD_P44	
•	78	PTD5	LCD_P45/ ADC0_SE6b	LCD_P45/ ADC0_SE6b	PTD5	SPI0_PCS2	UART0_CTS_b	FTM0_CH5		EWM_OUT_b	LCD_P45	
•	79	PTD6	LCD_P46/ ADC0_SE7b	LCD_P46/ ADC0_SE7b	PTD6	SPI0_PCS3	UART0_RX	FTM0_CH6		FTM0_FLT0	LCD_P46	
•	—	VSS	VSS	VSS								
•	80	PTD7	LCD_P47	LCD_P47	PTD7	CMT_IRO	UART0_TX	FTM0_CH7		FTM0_FLT1	LCD_P47	

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8.2 K30 Pinouts

The below figure shows the pinout diagram for the devices supported by this document. Many signals may be multiplexed onto a single pin. To determine what signals can be used on which pin, see the previous section.

NOTE

The 81 MAPBGA ballmap assignments are currently being developed.

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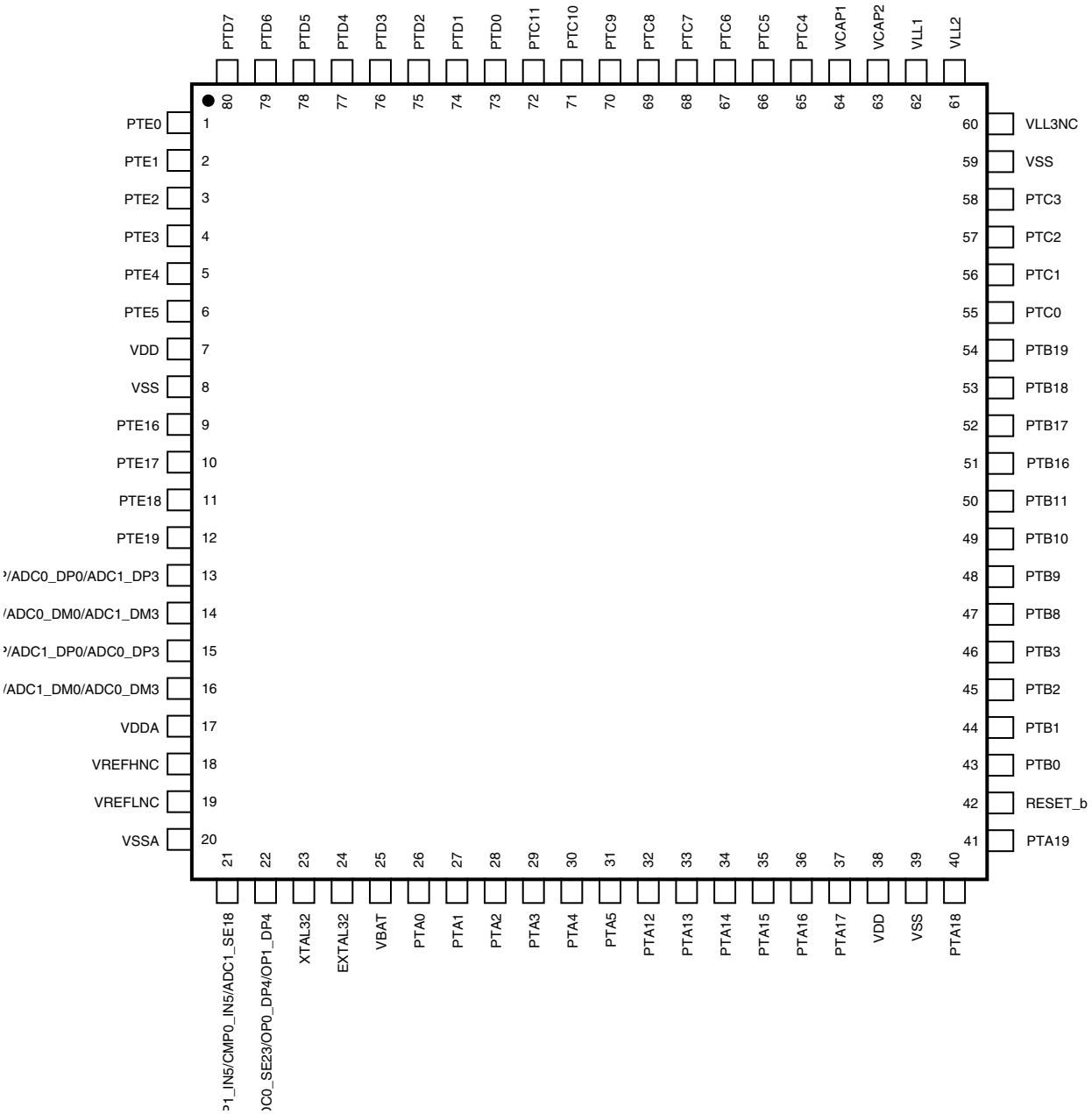

Figure 26. K30 80 LQFP Pinout Diagram

9 Revision History

The following table provides a revision history for this document.

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Table 43. Revision History

Rev. No.	Date	Substantial Changes
1	11/2010	Initial public revision
2	3/2011	Many updates throughout Corrected 81- and 104-pin package codes
3	3/2011	Added sections that were inadvertently removed in previous revision
4	3/2011	Reworded I_{IC} footnote in "Voltage and Current Operating Requirements" table. Added paragraph to "Peripheral operating requirements and behaviors" section. Added "JTAG full voltage range electricals" table to the "JTAG electricals" section.

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